

Online Bunch Length Monitoring for Storage Ring using a Fast Photodiode



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**Garam Hahn, Woojin Song, Changbum Kim, Dotae Kim (PAL,
Pohang), Ji-Gwang Hwang (Gangneung-Wonju Natl. Univ.)**

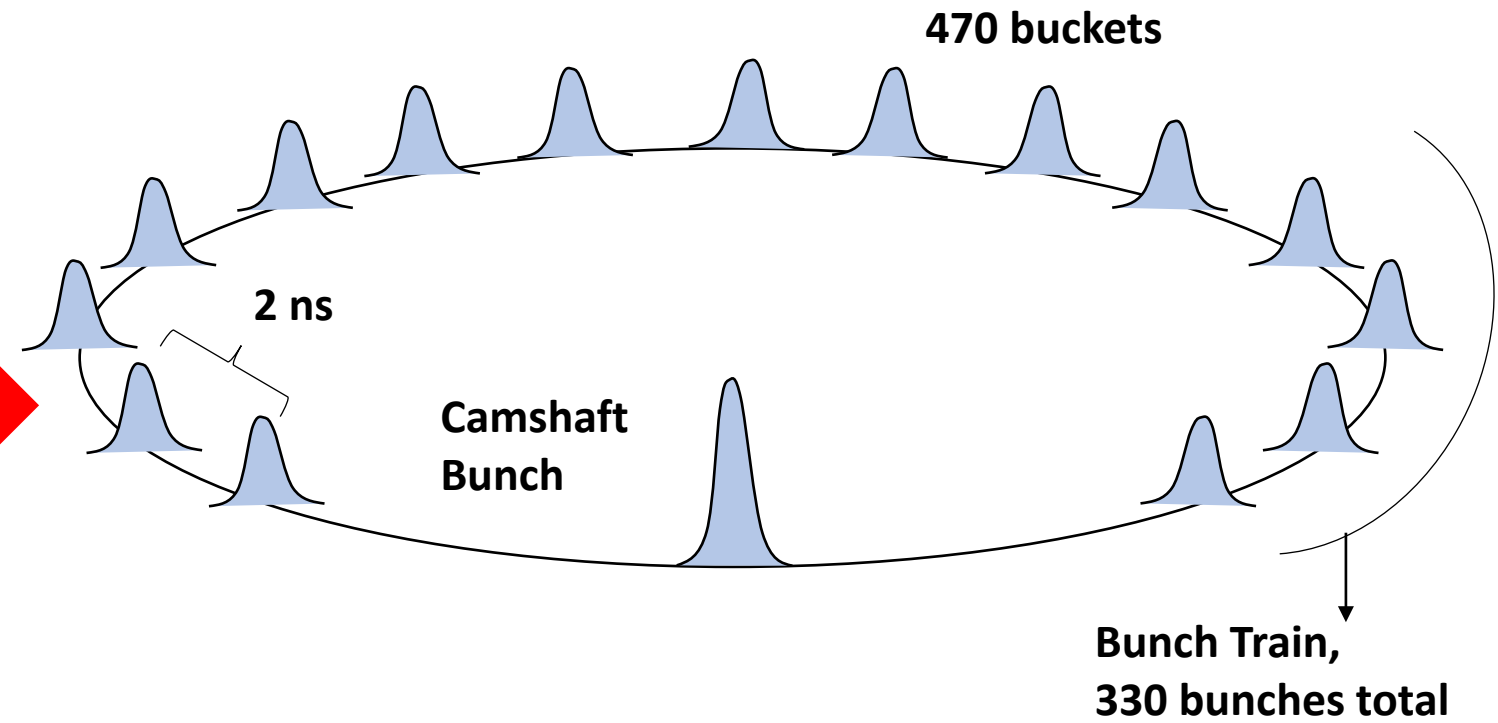


- Introduction
- Experimental Setup
- Analysis Method
- Result
- Summary



PLS-II Parameter	Value	Unit
Beam Energy	3	GeV
Beam Current	400	mA
Circumference	281.82	m
RF Frequency	499.97	MHz
RMS Bunch Length	21.3	ps

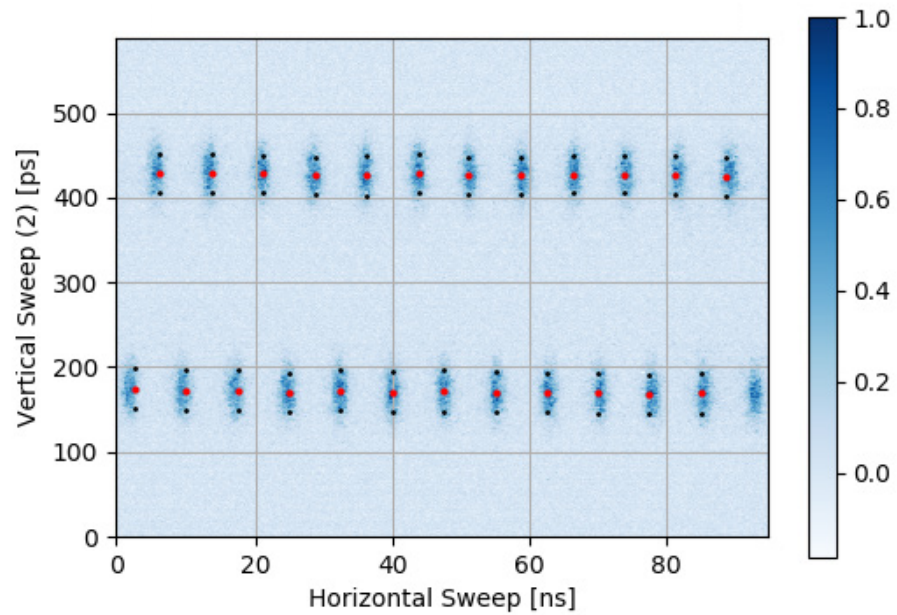
- PLS-II operates a hybrid filling pattern to support pump-probe experiments.
- Online information of bunch lengths and fill-pattern could be worth for users



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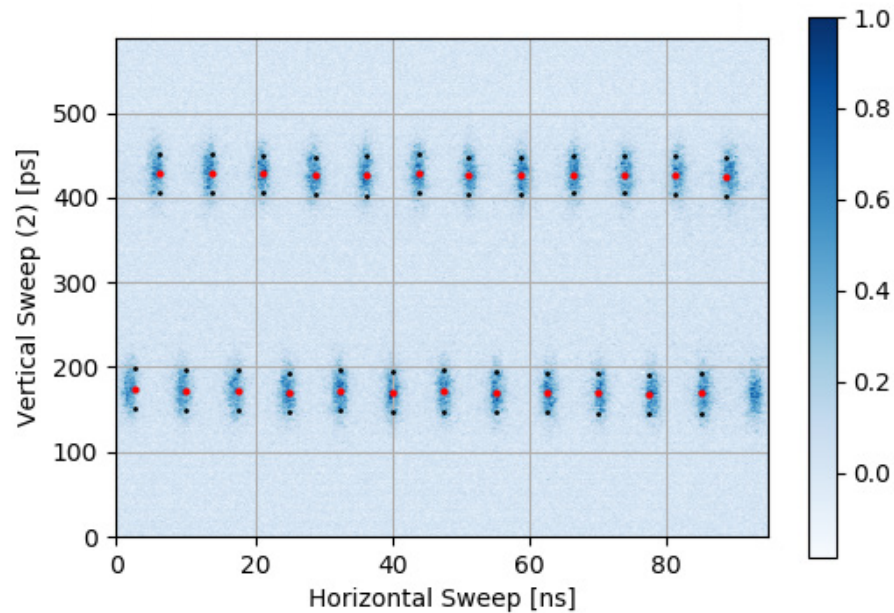
Bunch Length



Streak Camera

- High temporal resolution (< RMS 1 ps)
- Slow acquisition rate
- Incompatible for turn-by-turn measurements

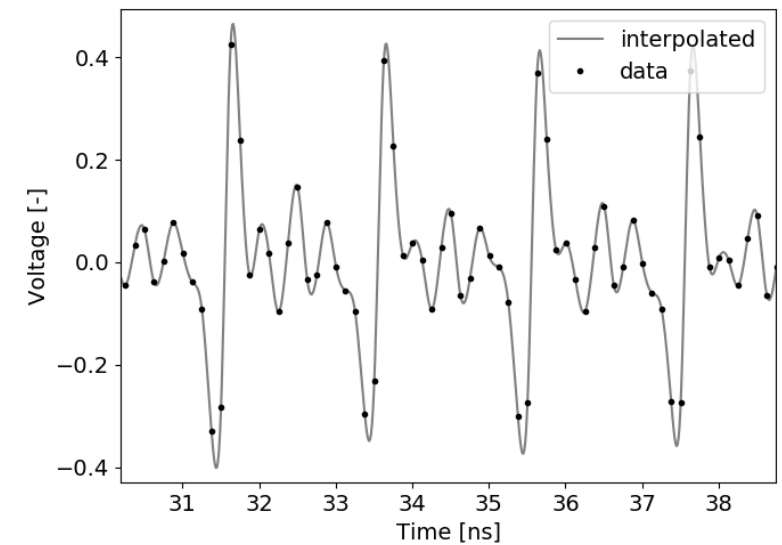
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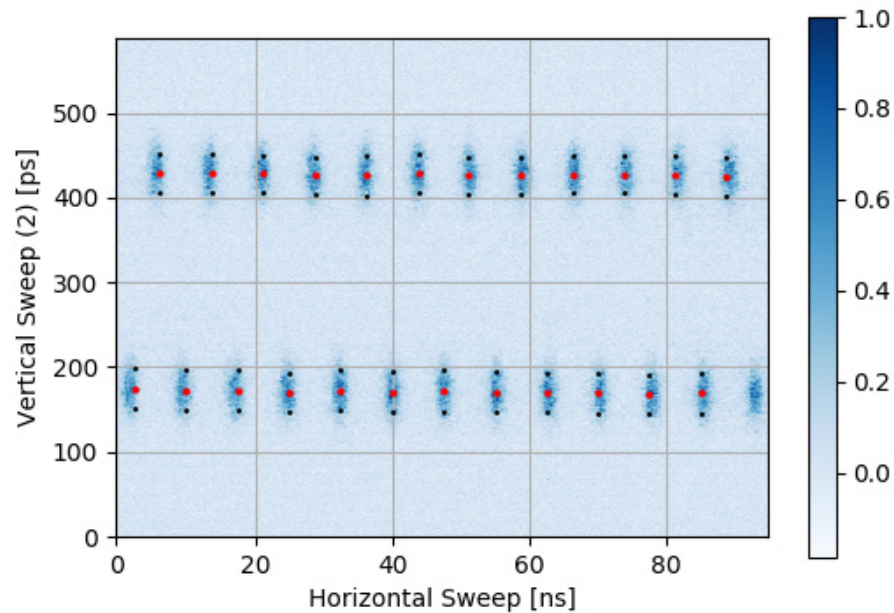
Fill-Pattern



BPM pick-up / FCT

- Fill-pattern monitoring
- Limited bandwidth
- Moderate accuracy
- Non-linear behavior causes an intolerable error

Bunch Length



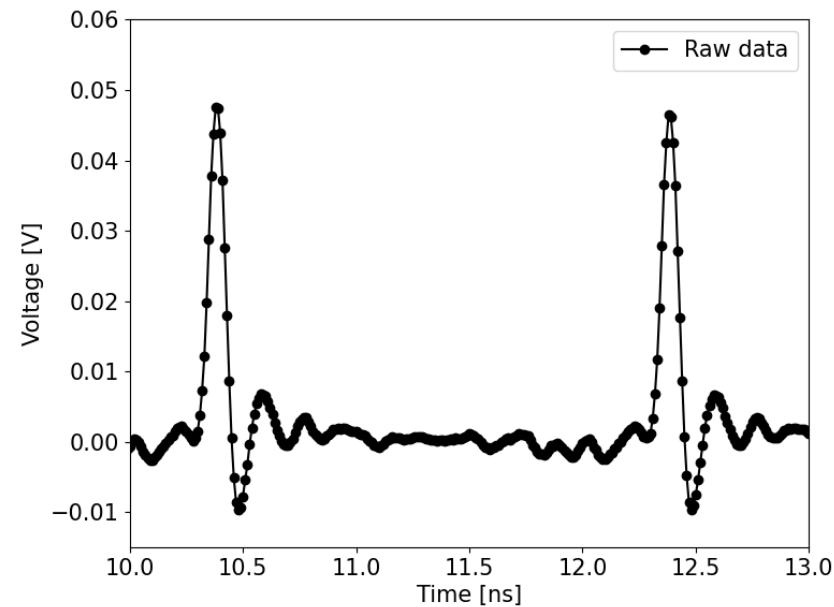
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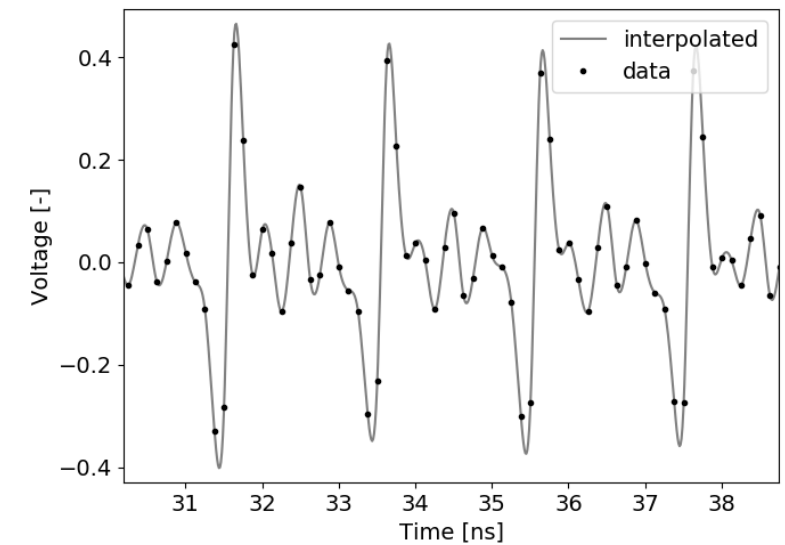
Bunch Length + Fill-Pattern

Fast Photodiode

- Intermediate resolution (~ 2 ps)
- Bunch length and fill-pattern real-time measurement



Fill-Pattern



BPM pick-up / FCT

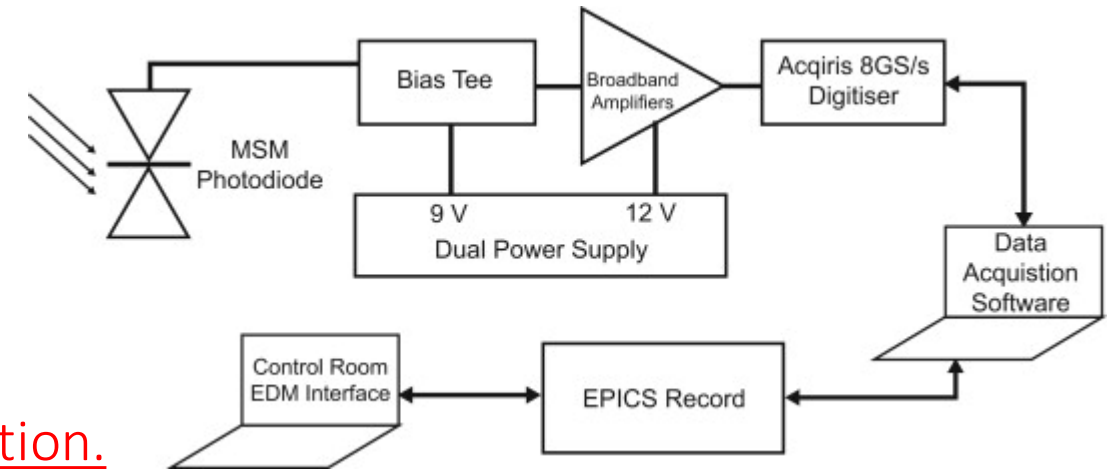
- Fill-pattern monitoring
- Limited bandwidth
- Moderate accuracy
- Non-linear behavior causes an intolerable error

- **Australian Synchrotron [1]**

- Successful online fill-pattern (FP) measurement
- We could not find analog input bandwidth information of bias tee, digitizer or cables.

→ We use similar experimental set-up

BUT chose all devices' ABW near 15 GHz for bunch length detection.



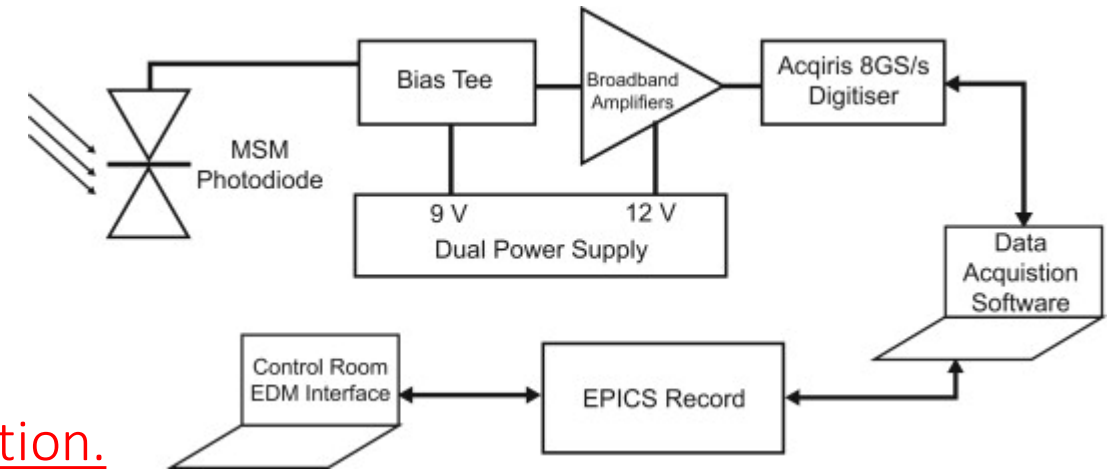
[1] D. J. Peake *et al.*, “Measurement of the real time fill-pattern at the Australian Synchrotron”, NIM. A. (2008)

• Australian Synchrotron [1]

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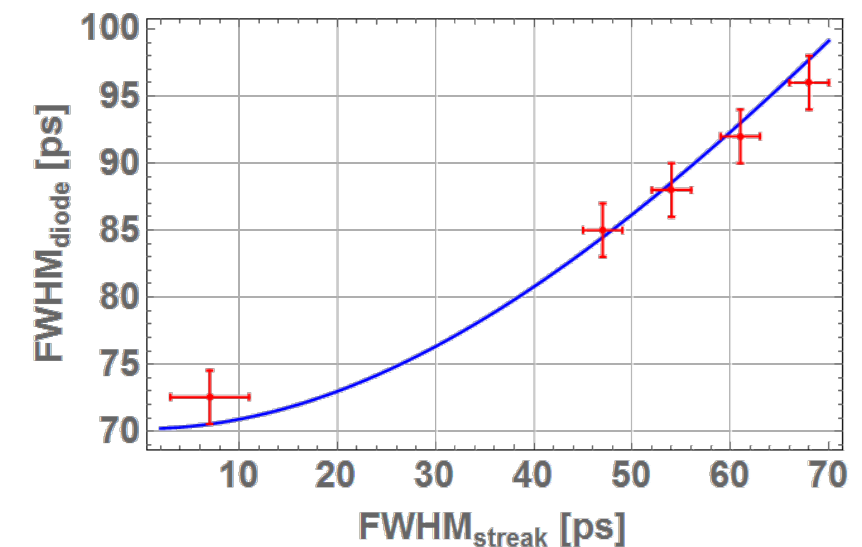


• Bessy-II, HZB [2]

- Successful online bunch length, fill-pattern, and phase measurement.
- Bunch length data fit result seemed valid locally.

→ We developed a new analysis method

to handle nonlinear frequency response of the system.

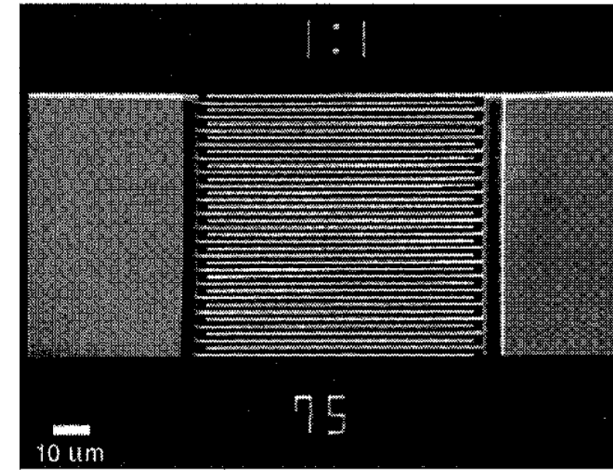


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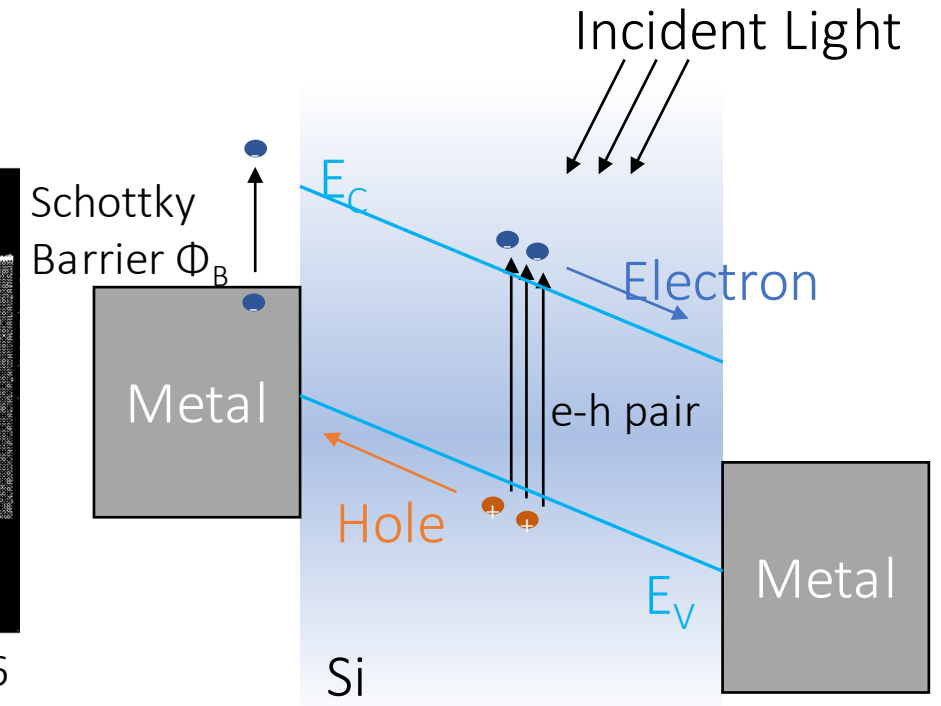
[2] J. Hwang, Bunch length measurement by using a fast photodiode, Private Discussion, (2019)

- Metal-Semiconductor-Metal Photodiode
 - Metal-semiconductor Junction
 - Schottky diode's potential barrier is ruled by the metal and silicon work functions.

MSM photodiode with wedge-comb structure has fast and strong response.



P. R. Berger, 1996

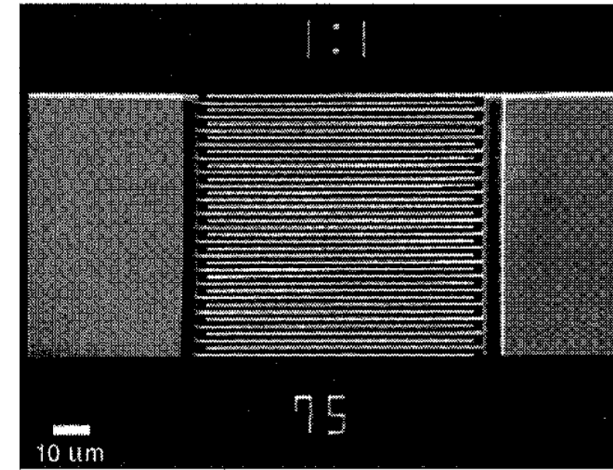


- Metal-Semiconductor-Metal Photodiode

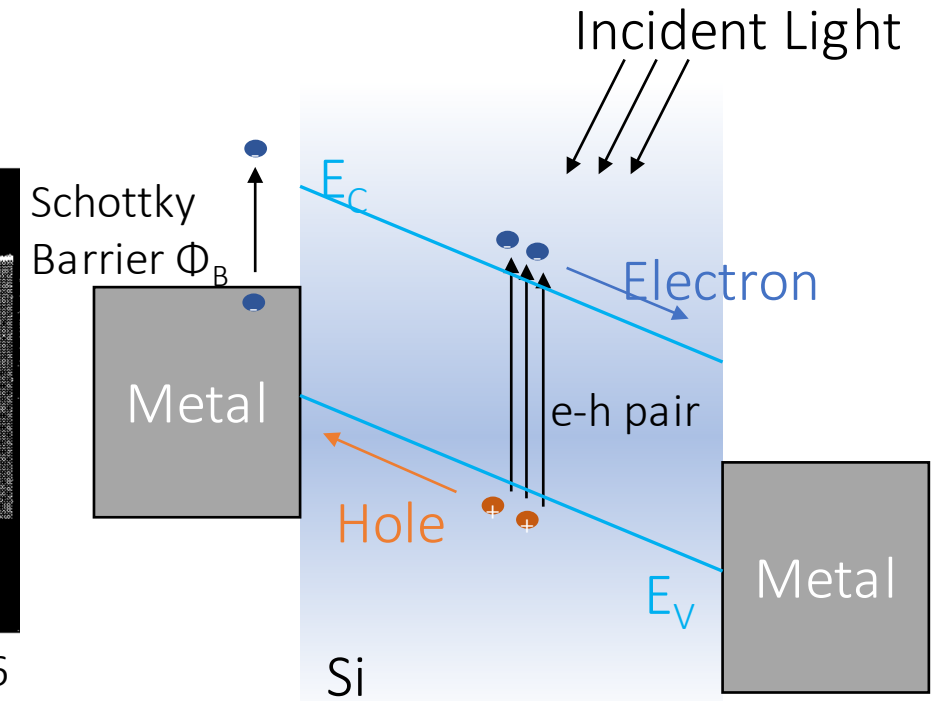
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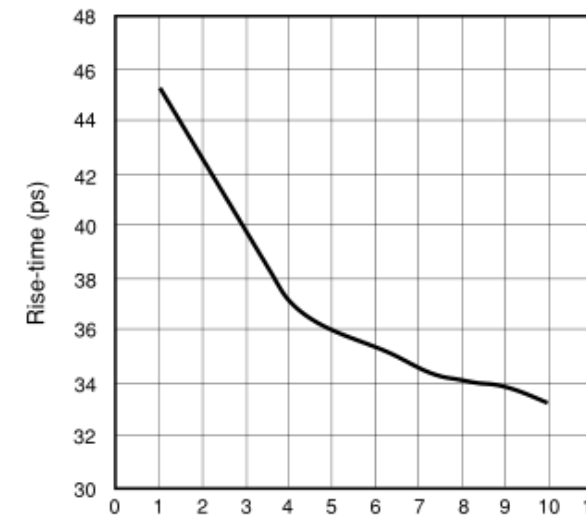


- Hamamatsu G4176-03
(GaAs MSM photodiode)

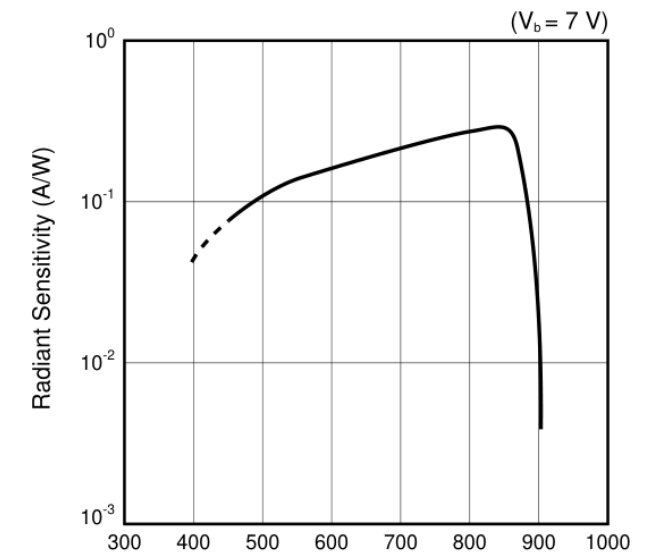
- Rise time ~ 35 ps @ 7 V bias
- Active area : 200 μm²
- Dark current : 100 pA @ Ta = 25 °C



G4176-03



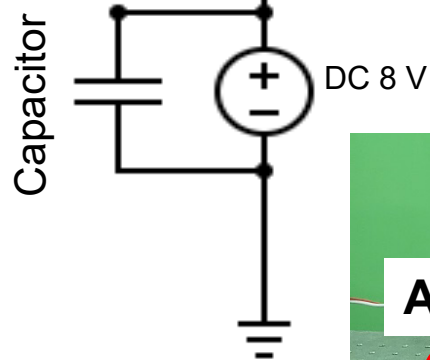
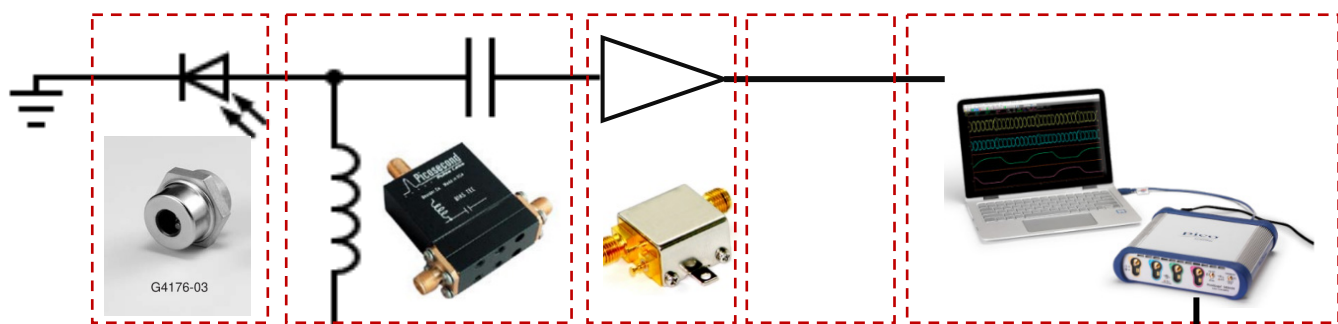
Rise time vs. Applied Voltage



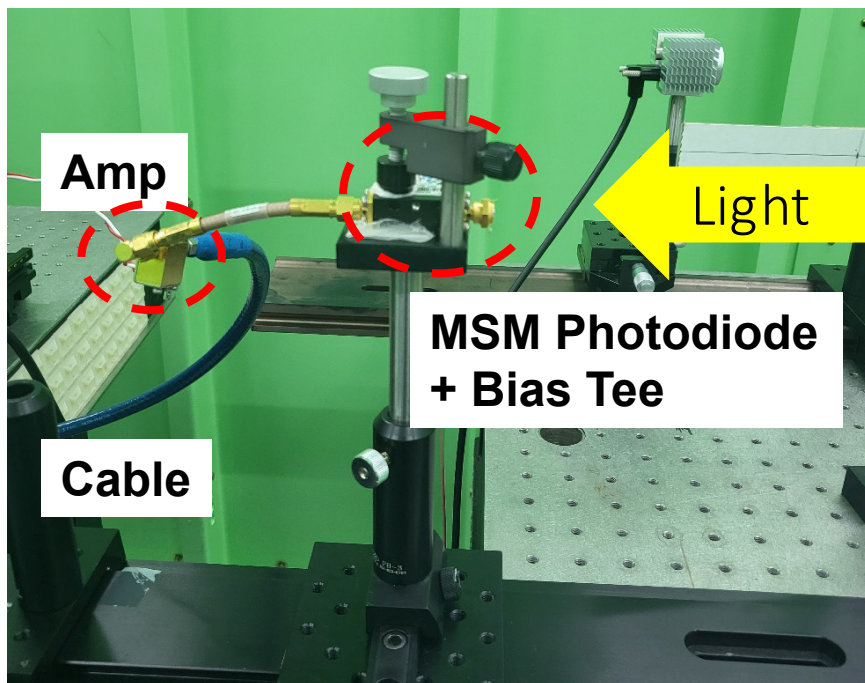
Spectral Response

Visible part (600~900 nm λ) of synchrotron radiation –

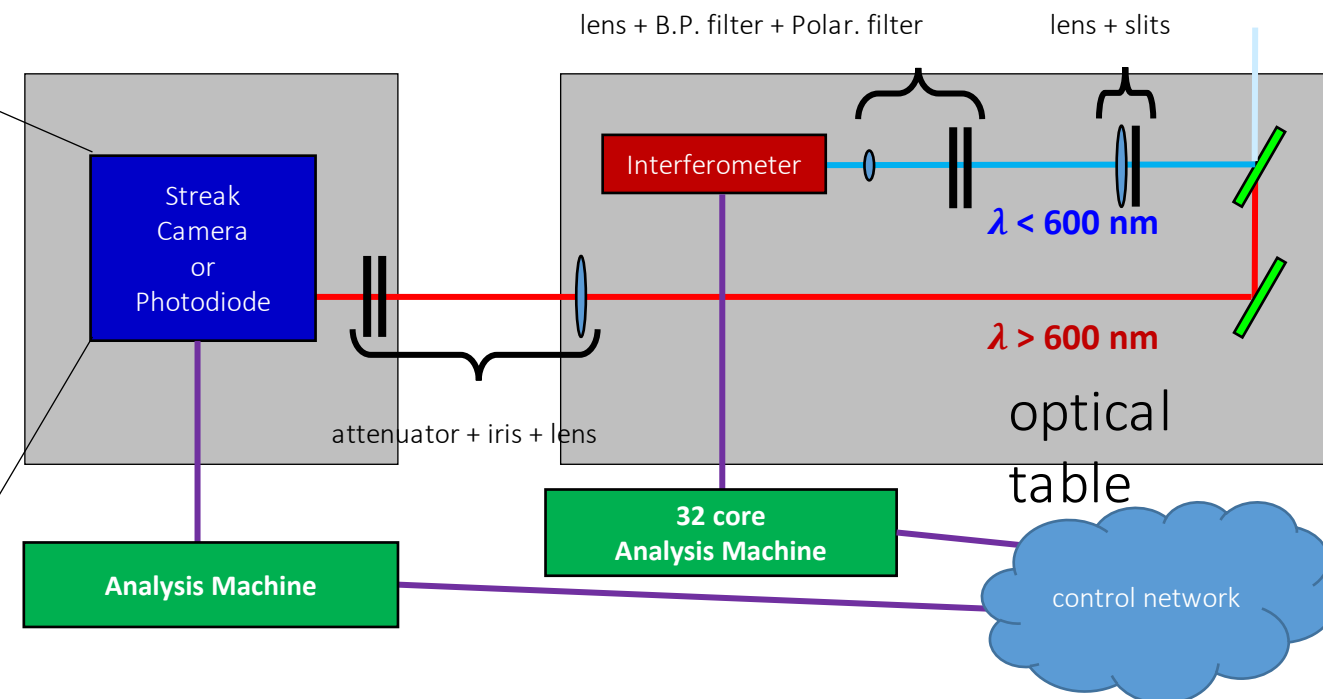
Photodiode – Bias Tee – Amp – Cable – Digitizer – PC



1 MHz Revolution Trigger



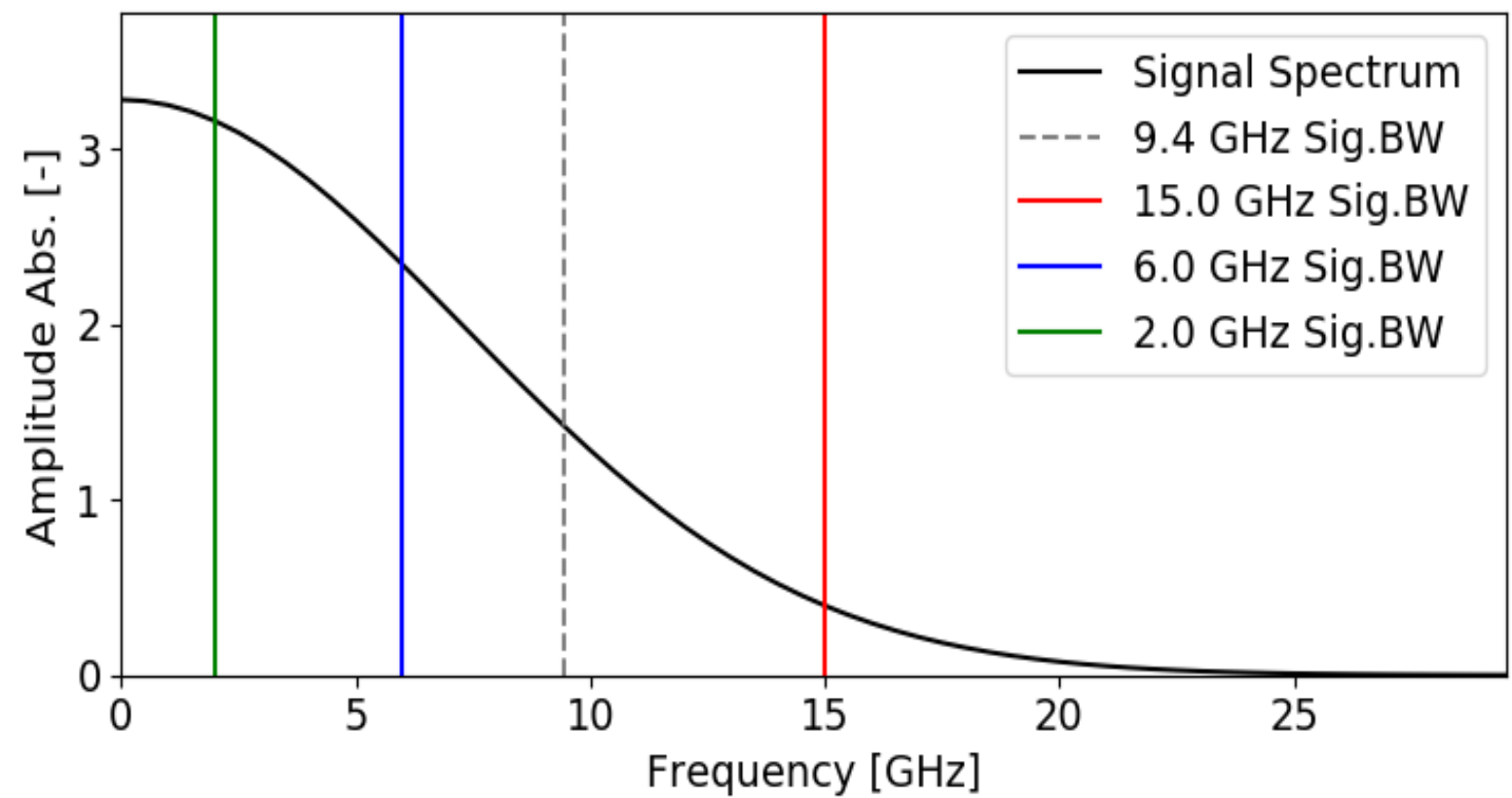
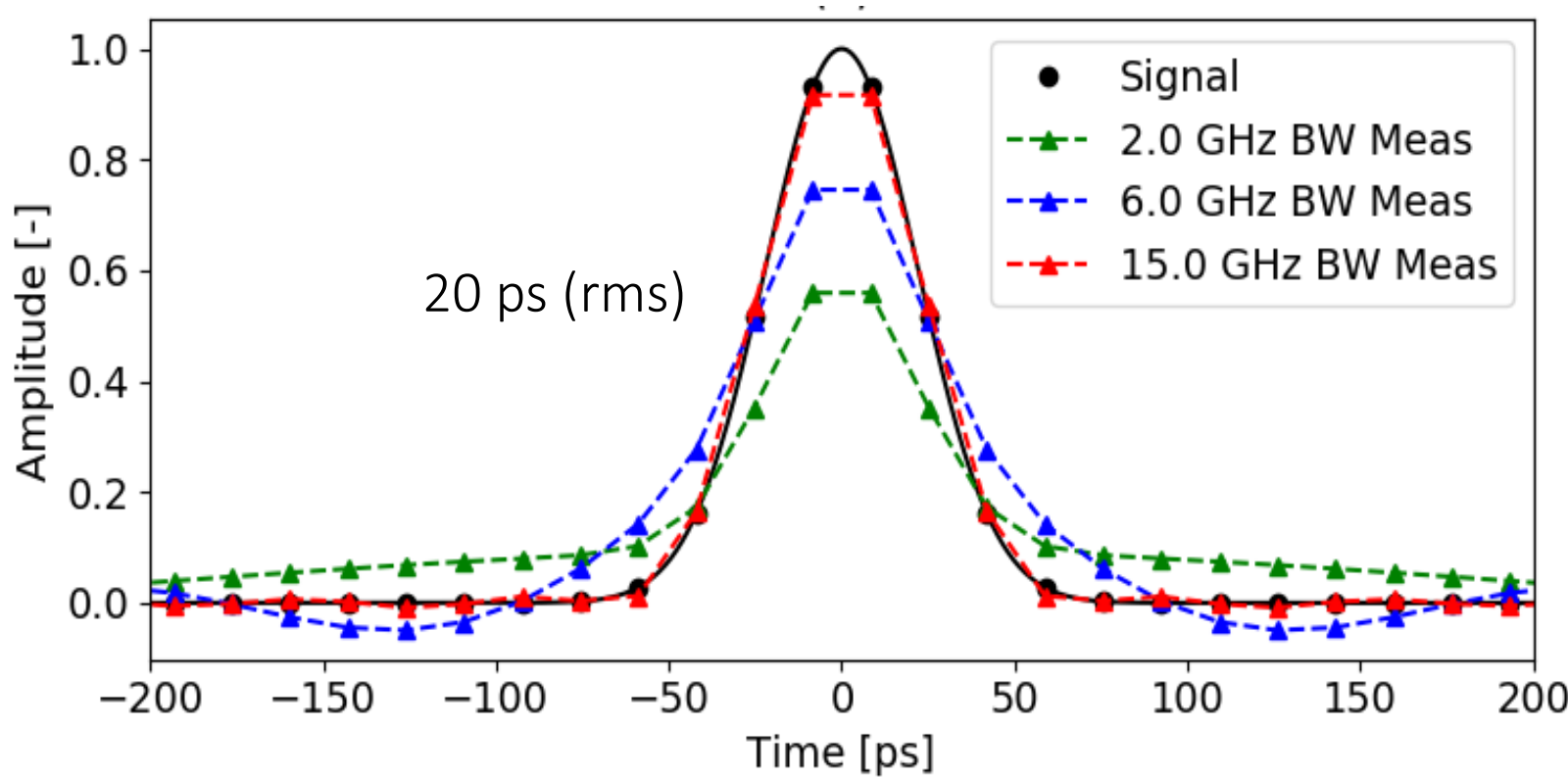
Visible Light Beam Diagnostic Hutch (BL1B)



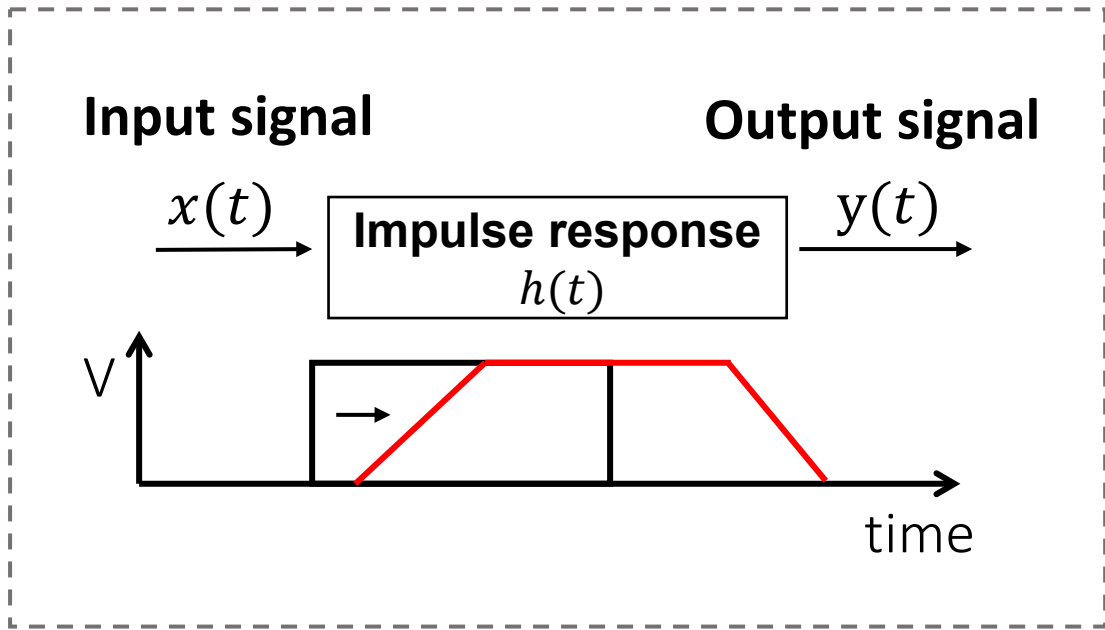
- To maximize gain and efficiency, dichroic mirror was used.
 - higher than 600 nm for photodiode
 - lower for interferometer
- Beam splitter was used for simultaneous measurement with photodiode and streak camera.
- Multi-channel DC P/S 8 - 12V was installed to feed the voltage to the photodiode (connected at the bias tee) and the amplifier.



Component	Model	Analog Bandwidth (-3 dB)	Etc.
Photodiode	G4176-03, Hamamatsu	~ 10.4 GHz *	No Freq. Response Info.
Bias Tee	5541A, Picosecond(Tektronix)	26 GHz	
Amplifier	ZX60-14012L-1+, Mini-Circuits	14 GHz	
Cable	Lab-made	26.5 GHz	
Digitizer	Picoscope9404-16, Pico Technology DPO71304SX, Tektronix	16 GHz 13 GHz	2 TS/s sequential, 0.5 GS/s real time sample 50 GS/s real time sample



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- The input signal is reconstructed by analytically deconvolving the output signal with a Gaussian kernel.
- The system's impulse response is used as a deconvolution kernel.

$$y(t) = x(t) * h(t) = \int x(\tau)h(t - \tau)d\tau$$

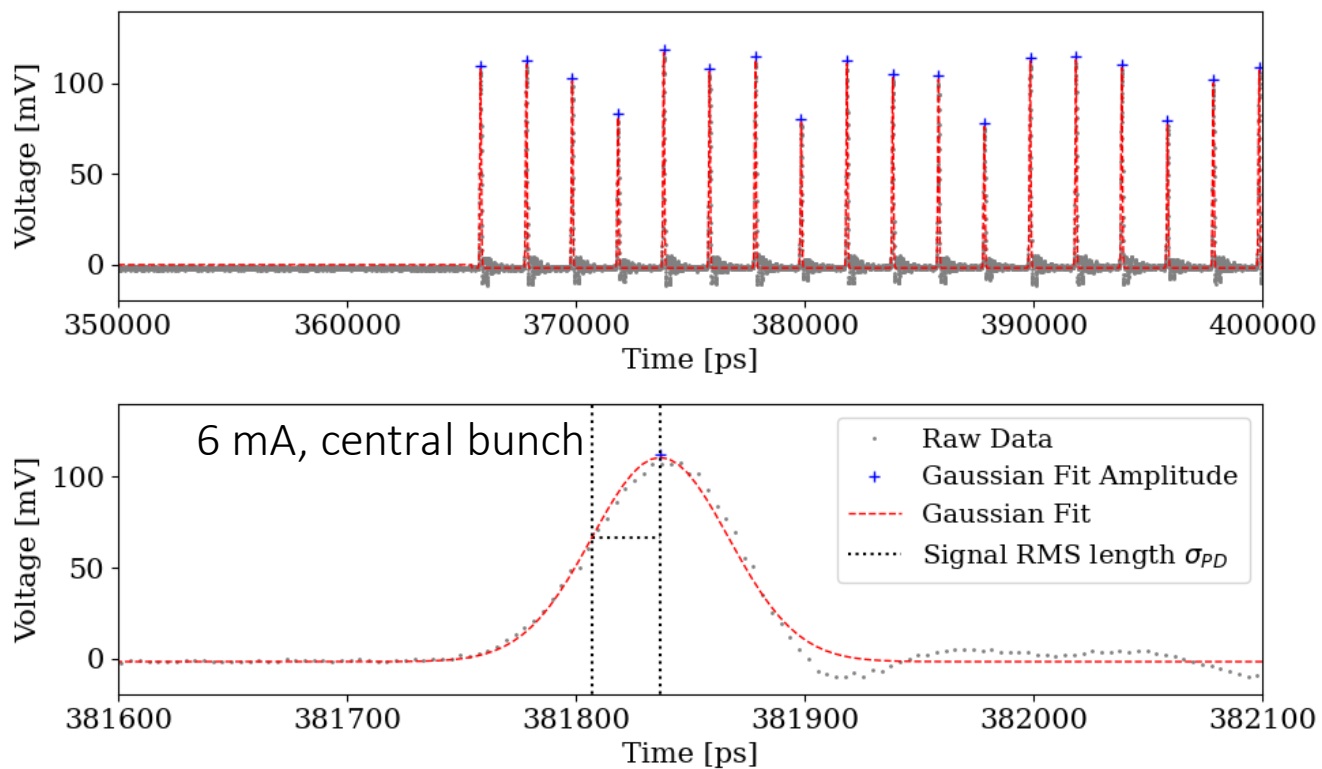


System response function

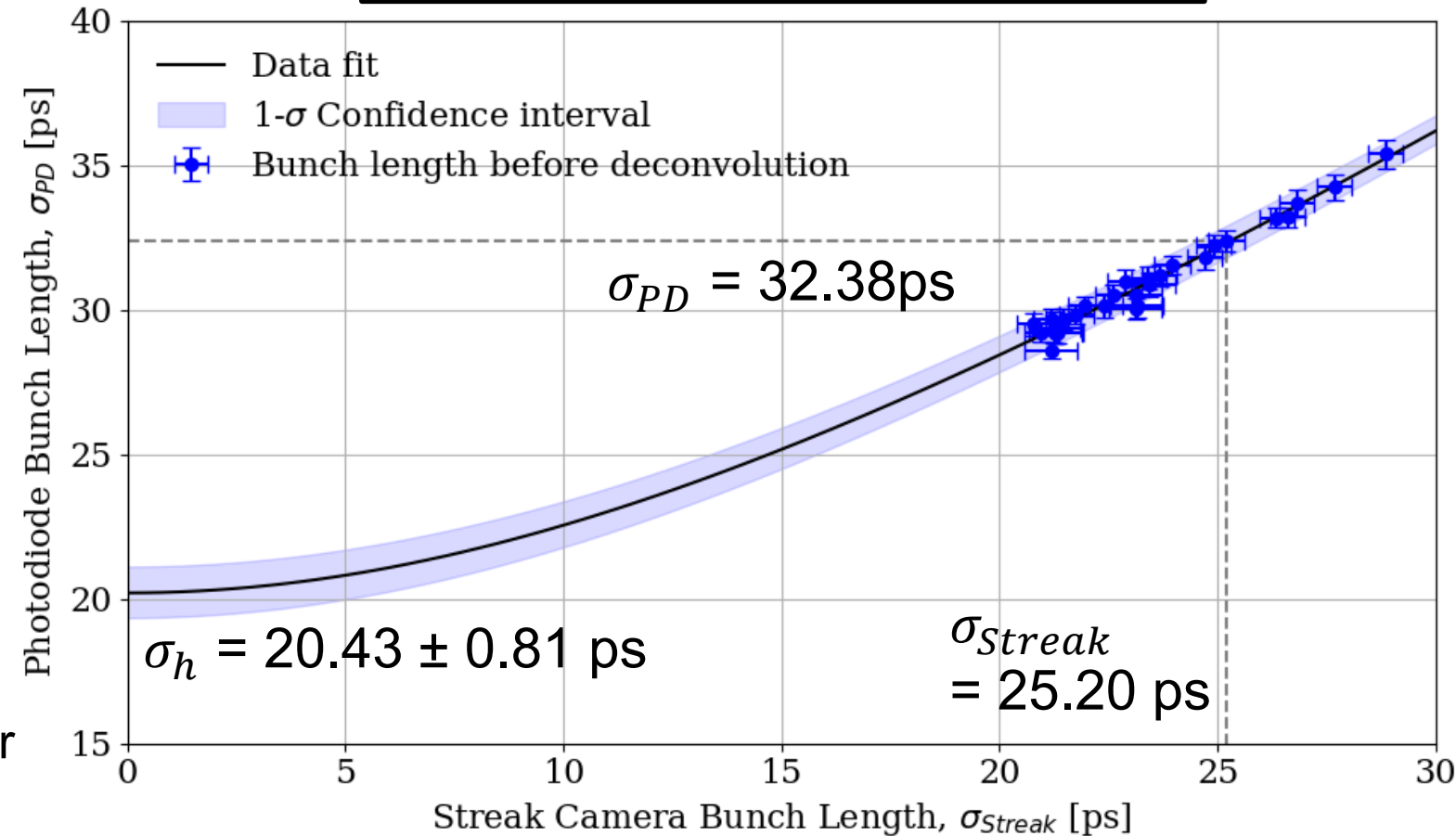
$$: h_{sys} = h_{PD} * h_{bias T} * h_{amp} * \dots$$

$$\sigma_y^2 = \sigma_x^2 + \sigma_h^2$$

Analytic Gaussian Deconvolution	
Pros	<ul style="list-style-type: none"> • Practical • Fast
Cons	<ul style="list-style-type: none"> • Inaccuracy (Error with Gaussian assumption)



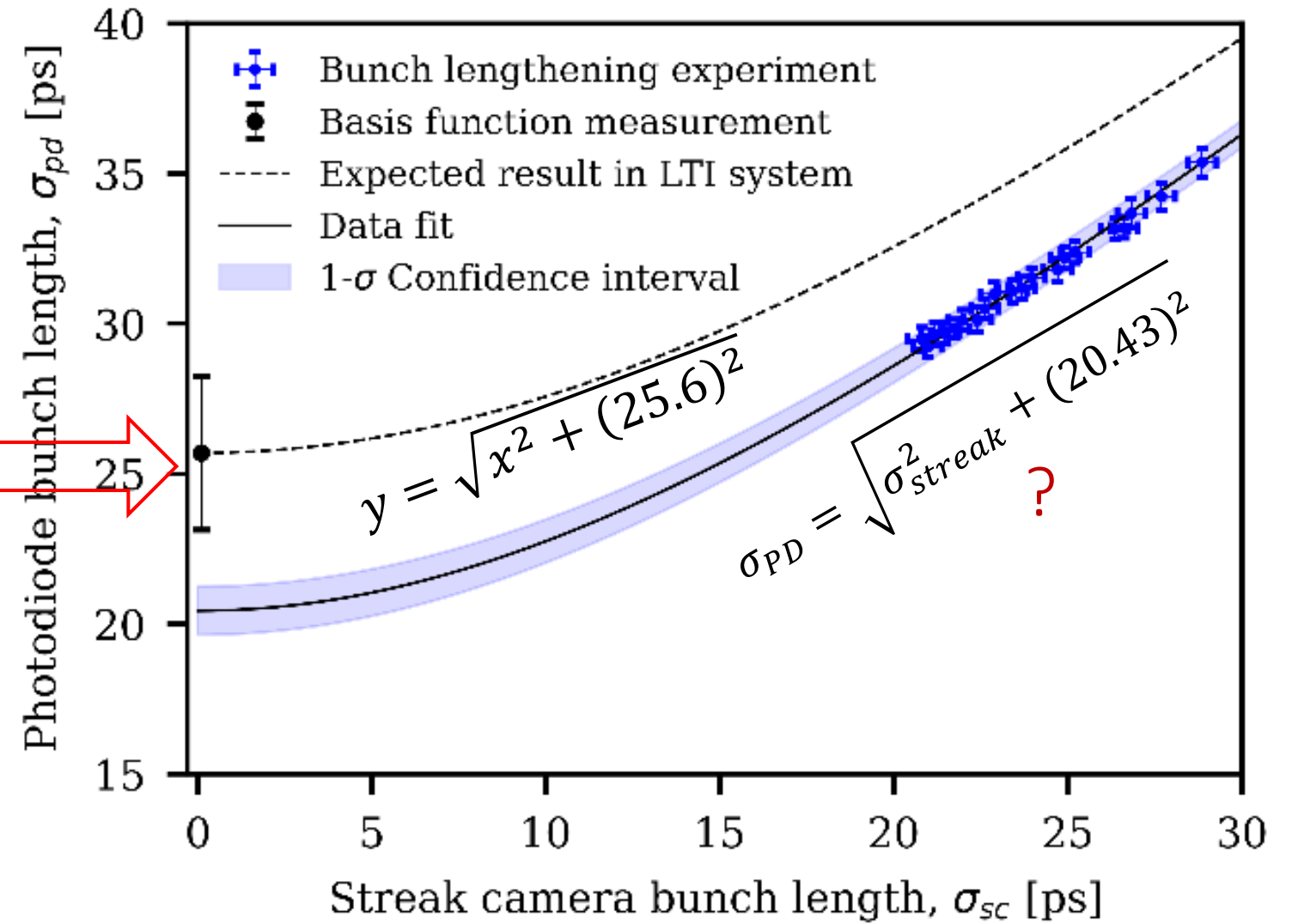
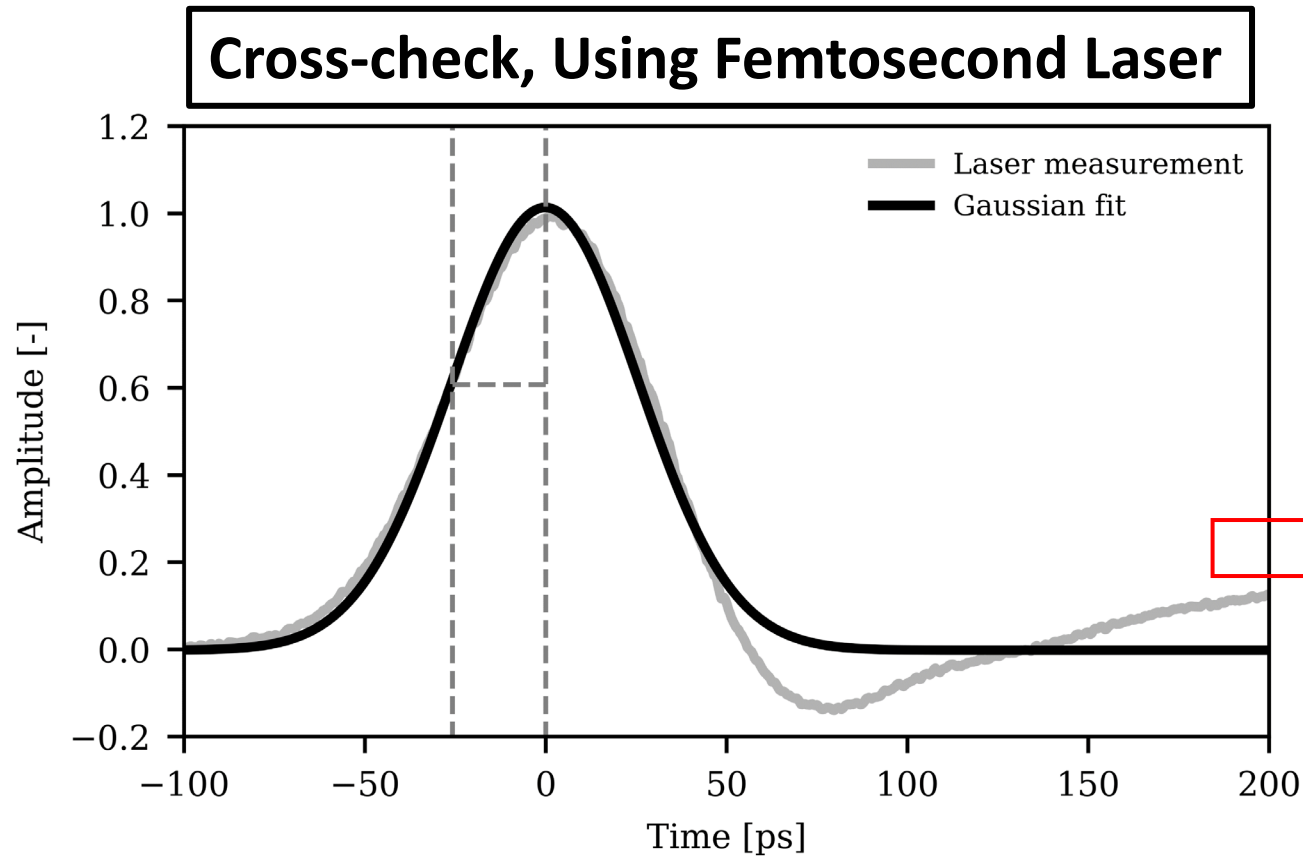
Bunch Length Measurement



- The noise level (without beam, room temperature, hutch-door closed) was equivalent to a bunch current of $3 \mu\text{A}$.
- The wideband system enables the bunch-resolved current measurement.
- Applying the fit form of typical Gaussian deconvolution, we obtained a calibration curve for photodiode measurement.
- Is the Point Spread Function $\sigma_{h,AGD}$ true?

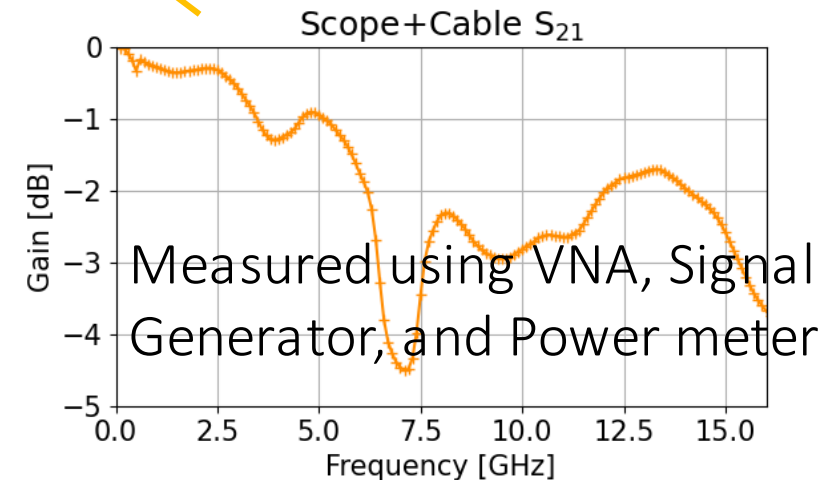
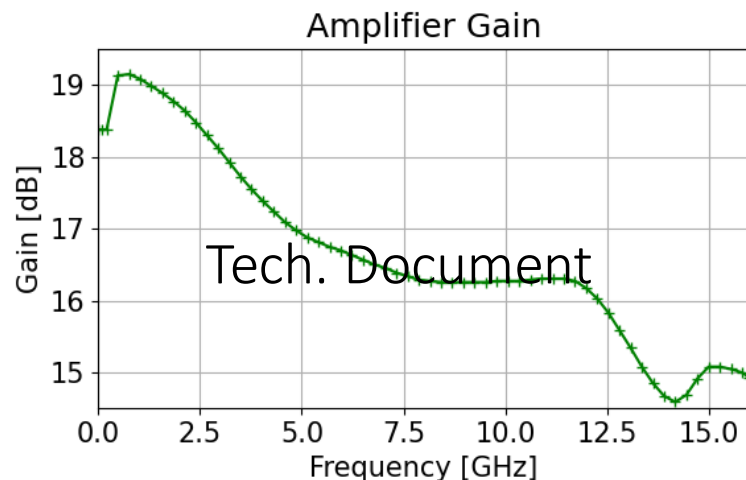
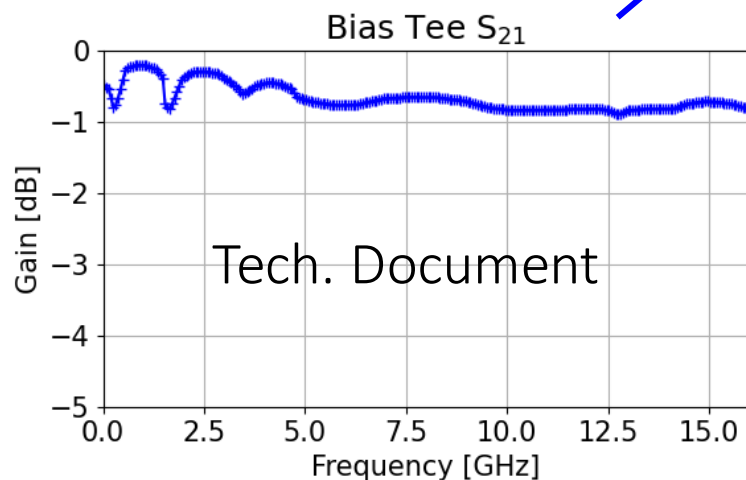
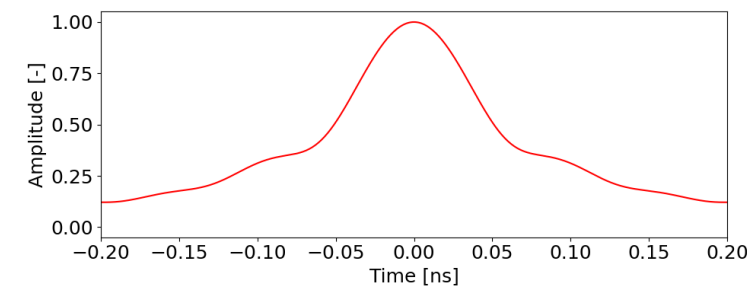
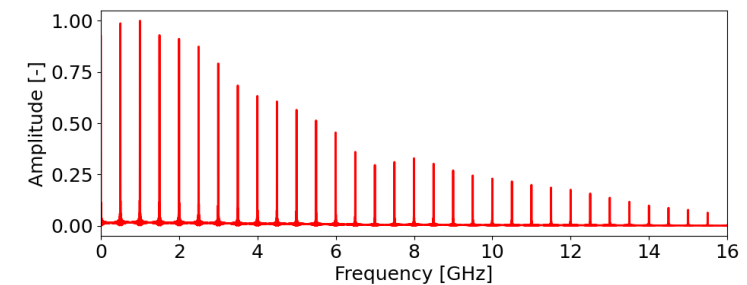
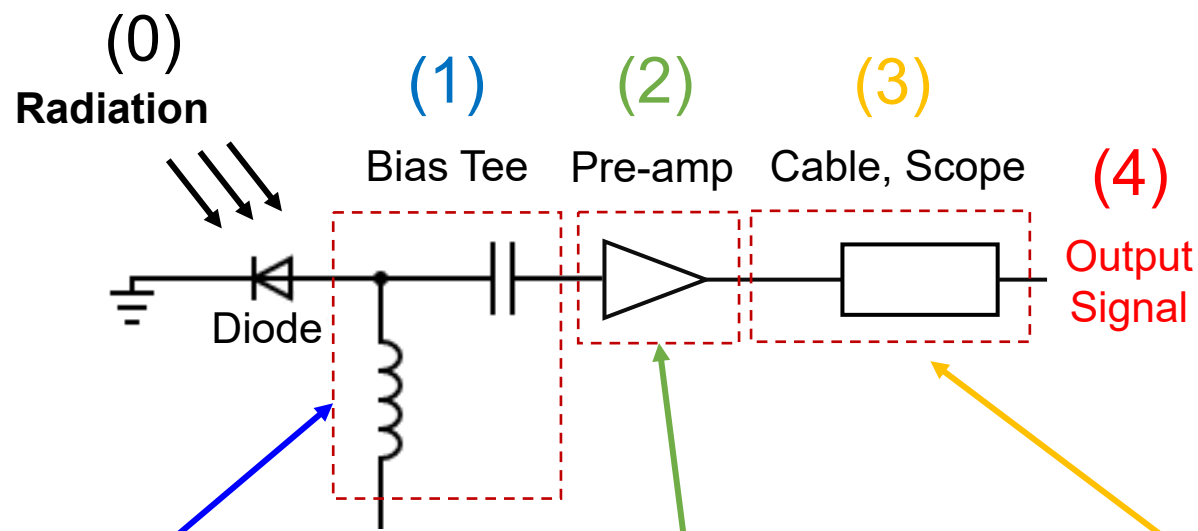
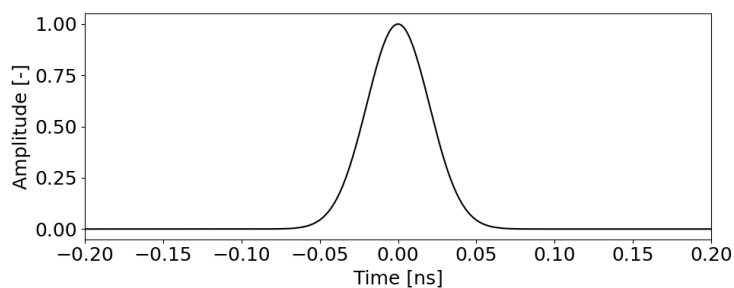
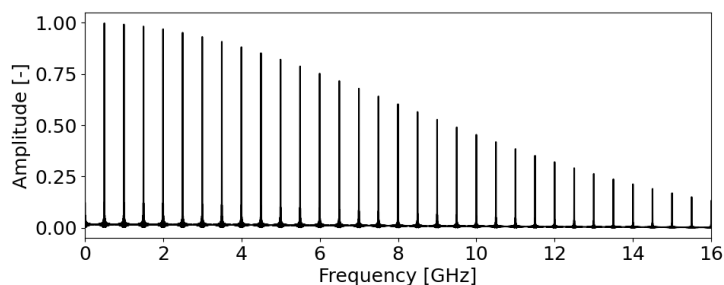
$$\text{Fit form : } \sigma_{PD} = \sqrt{\sigma_{streak}^2 + A^2}$$

$$\text{Fit result : } A \Rightarrow \sigma_{h,AGD} = 20.43 \pm 0.81 \text{ ps}$$



- The PSF was measured with a laser pulse width of ~ 200 fs, as a delta function.
- RMS PSF(Gaussian Fit) was obtained about 25.68 ± 2.56 ps which is way out of 1-sigma confidence interval.

- AGD PSF is inconsistent with the measured response function !



→ The measured signal is distorted strongly by the frequency response of analog components.

- Ultra-fast Photodiode**

- rise time(t) = ~ 35 ps @ 7 V (bias)
- Eq. bandwidth = $0.35/t \sim 10$ GHz
- Eq. point spread function = 20.7 ps

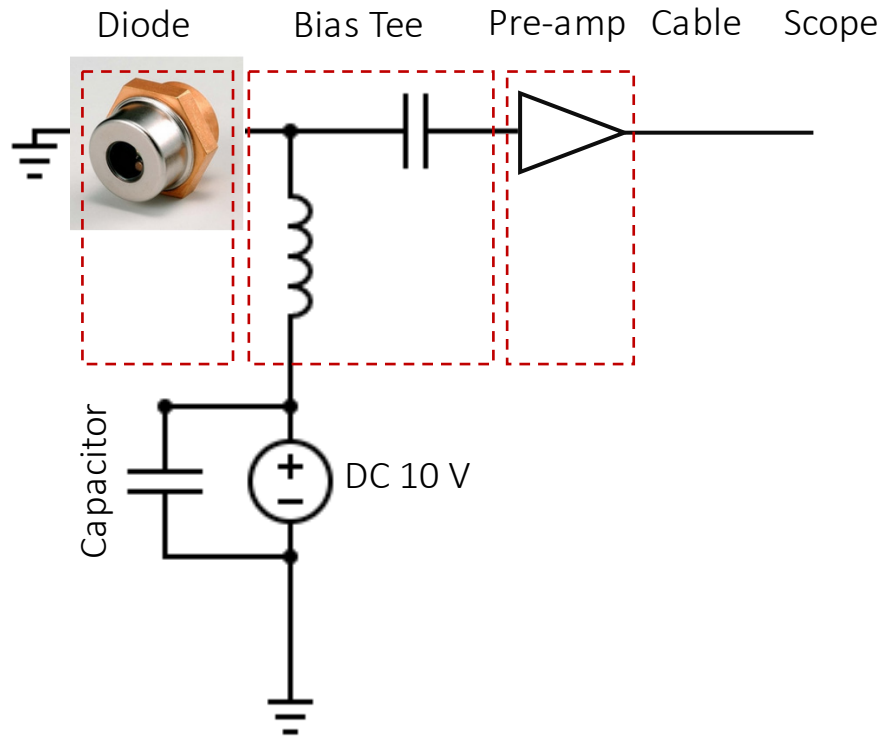
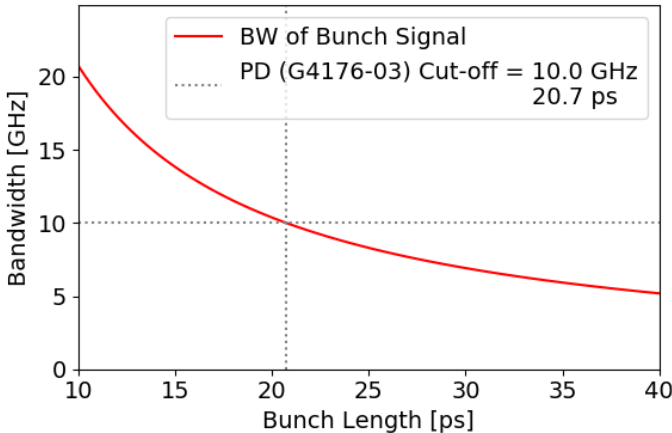
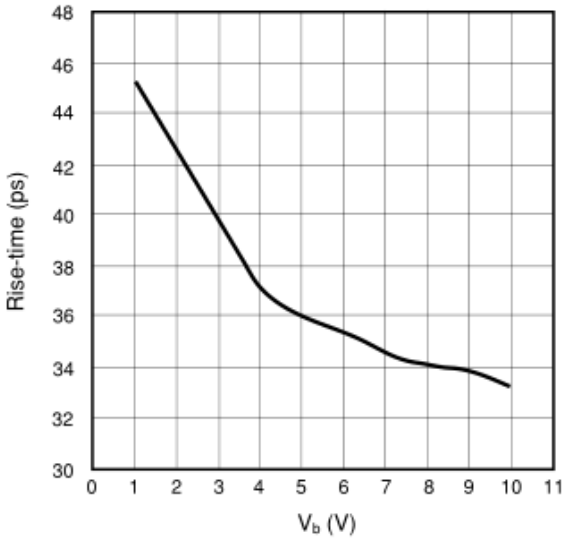
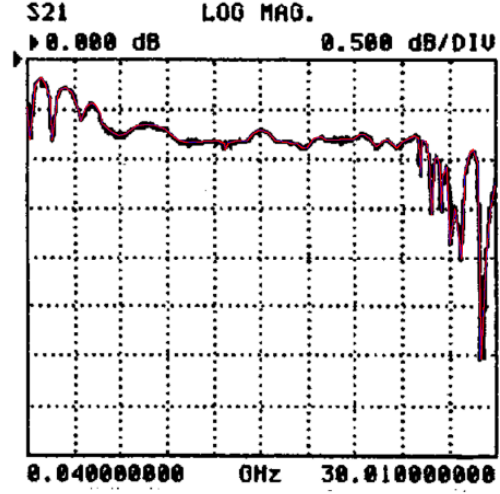


Figure 3: Rise Time vs. Applied Voltage (G4176-03)



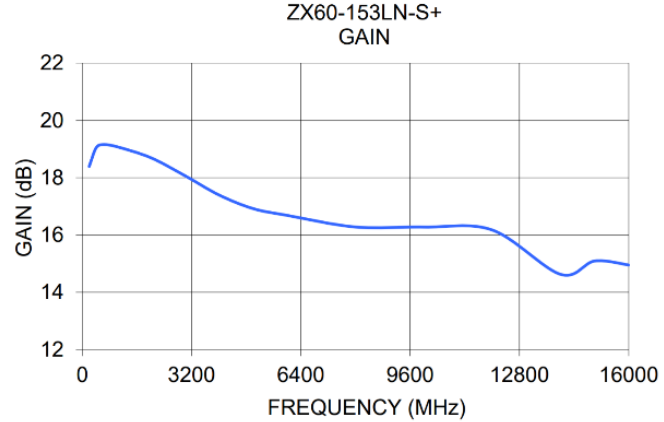
- Bias Tee**

- Gain



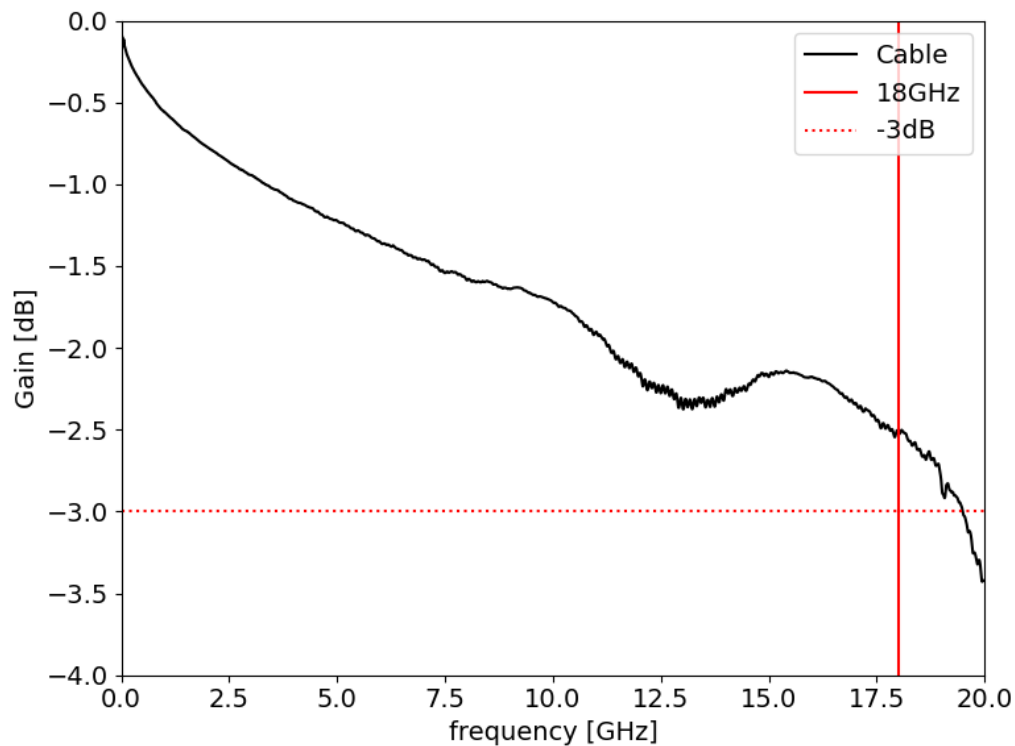
- Pre-amp**

- Gain



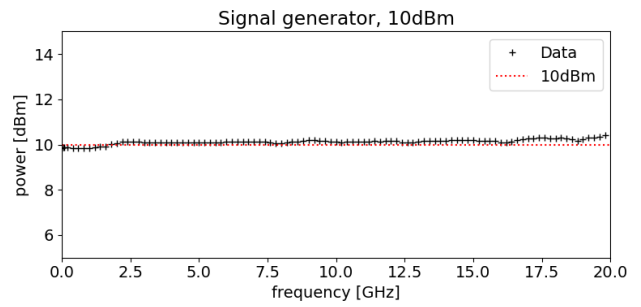
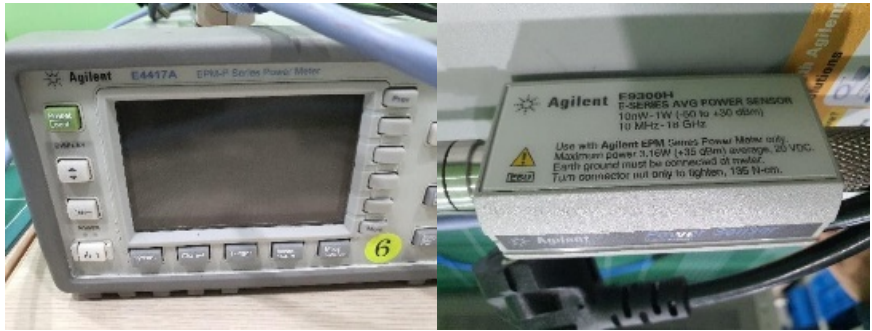
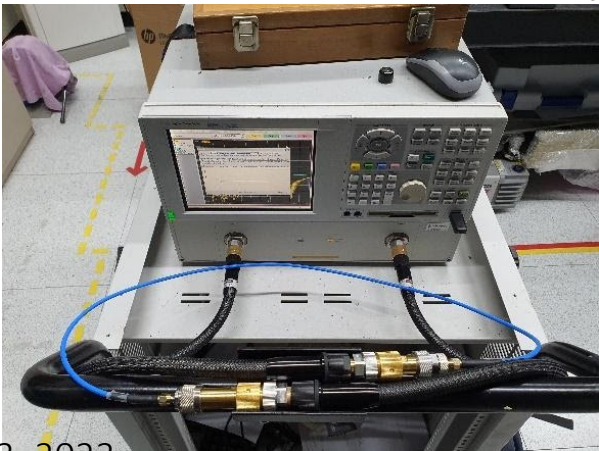
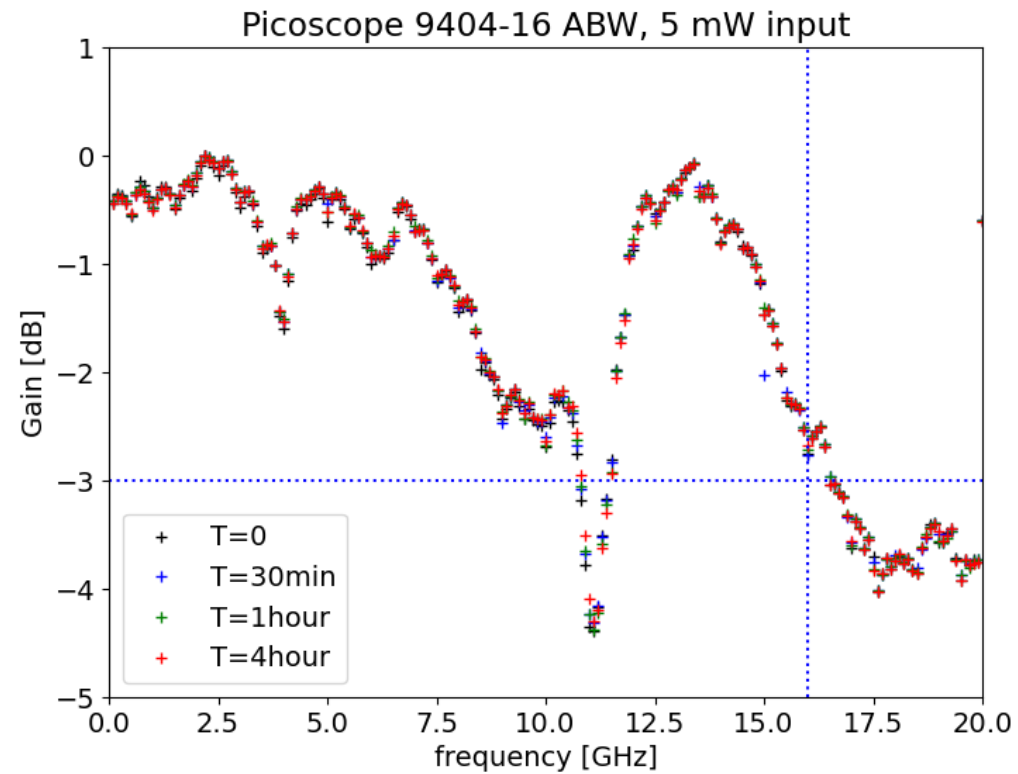
- Cable ABW Measurement**

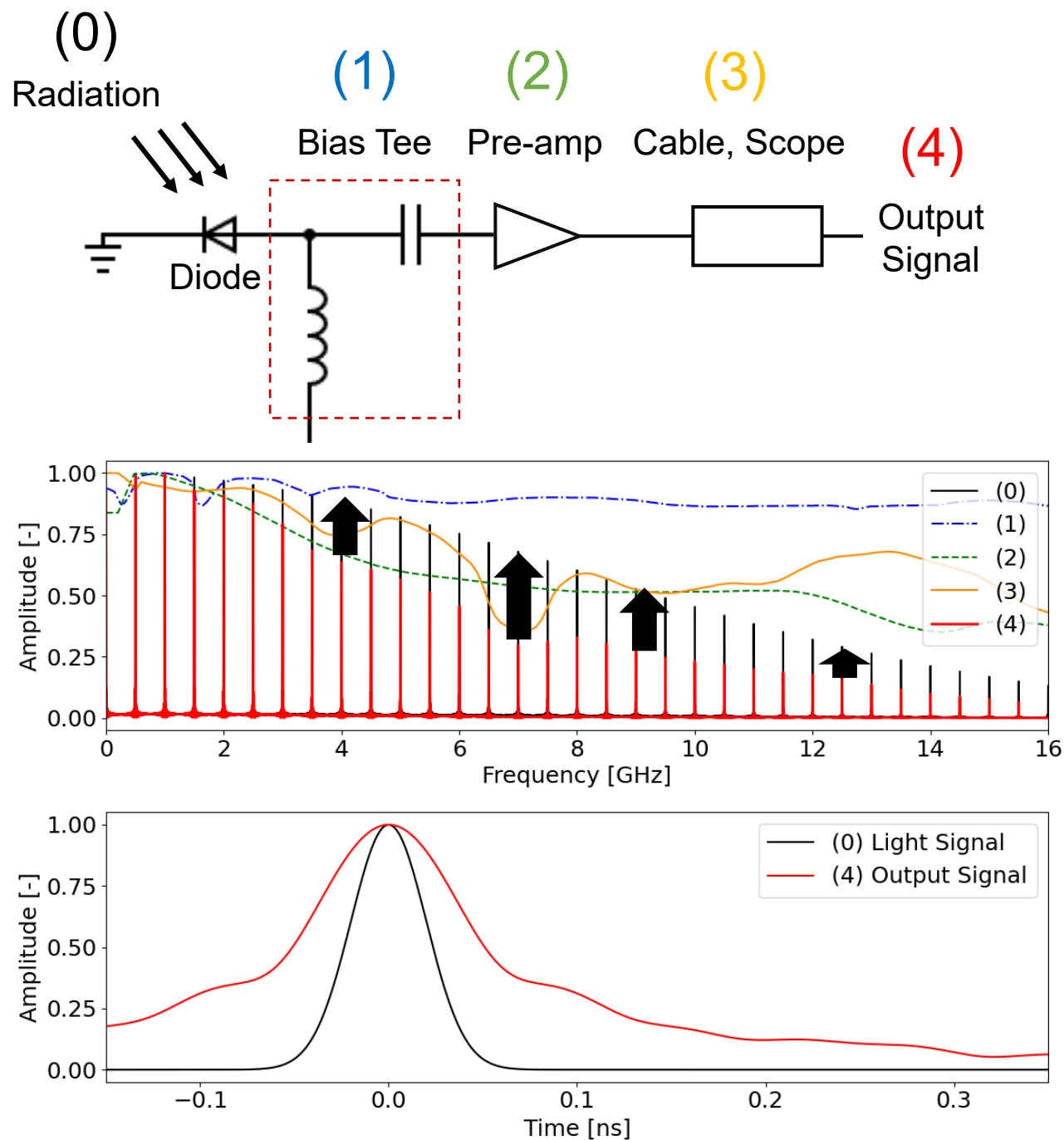
- Tr. Ratio (S21, **VNA**)
- Spec. was 26.5 GHz but obtained 19.5 GHz as -3 dB level



- Scope ABW Measurement (16 GHz-ABW, 2 TS/s EQ)**

- Tr. Ratio -> Gain (By well calibrated signal generator, we scanned frequency, and we measured voltage level at the digitizer)





1. Calculate the overall frequency response map R by convolution of all real frequency response maps

$$R(\omega) = R_1(\omega) \cdot R_2(\omega) \cdot R_3(\omega) \cdot R_4(\omega)$$

2. Measurement data was Fourier-transformed, And recovered by R

$$h'(t) = F^{-1} \left[\frac{F[h(t)]}{R(\omega)} \right] \quad \begin{matrix} F : FFT \\ F^{-1} : iFFT \end{matrix} \quad \text{Loop over}$$

3. To find the bunch length, calculate Gaussian fit, FWHM or whatever

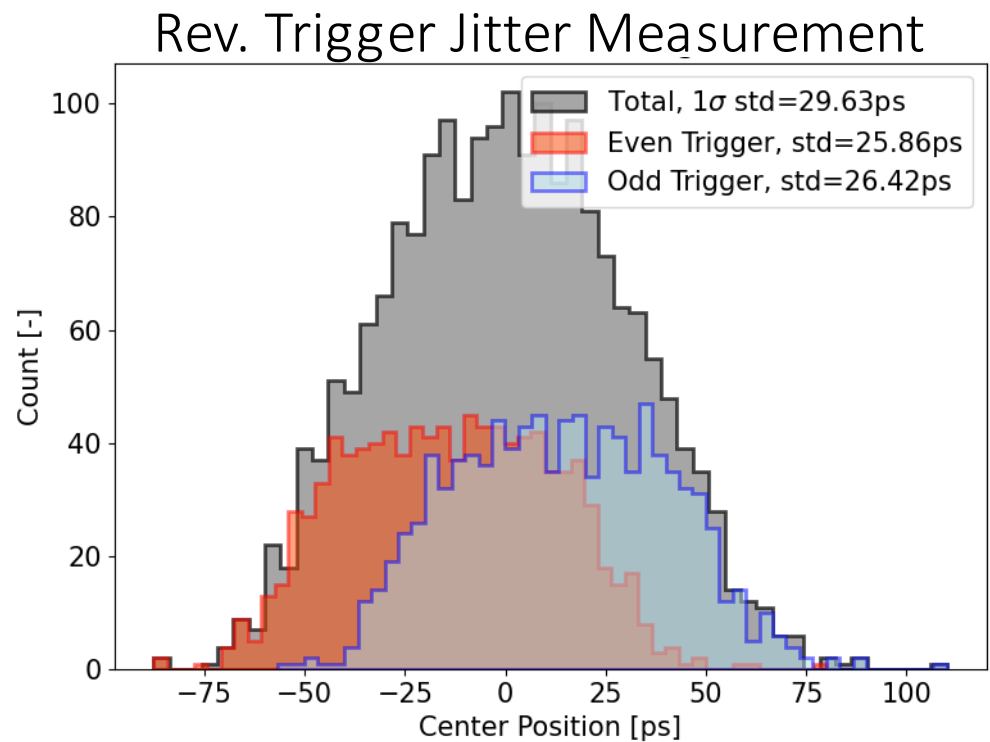
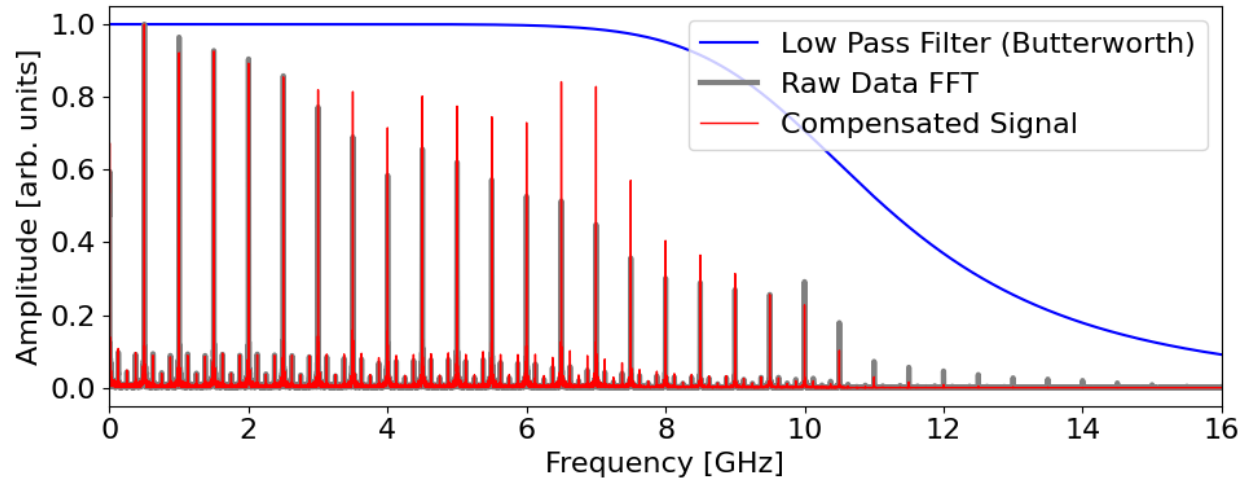
Numerical Compensation

Pros

- Still fast
- Accurate

Cons

- Frequency response can be changed according to circumstance. (ex. Temp, Connection ...)



1. Calculate the overall frequency response map R by convolution of all real frequency response maps

$$R(\omega) = R_1(\omega) \cdot R_2(\omega) \cdot R_3(\omega) \cdot R_4(\omega)$$

- 1.1 Accumulate data to reduce error caused by revolution trigger jitter (Typically 30-120 seconds using the Picoscope9400. We are currently using Tektronix DPO71304SX which is independent from the Rev. trigger jitter)

- 1.5. Apply low pass filter G (Butterworth, -3 dB at 16 GHz), to remove HF noise

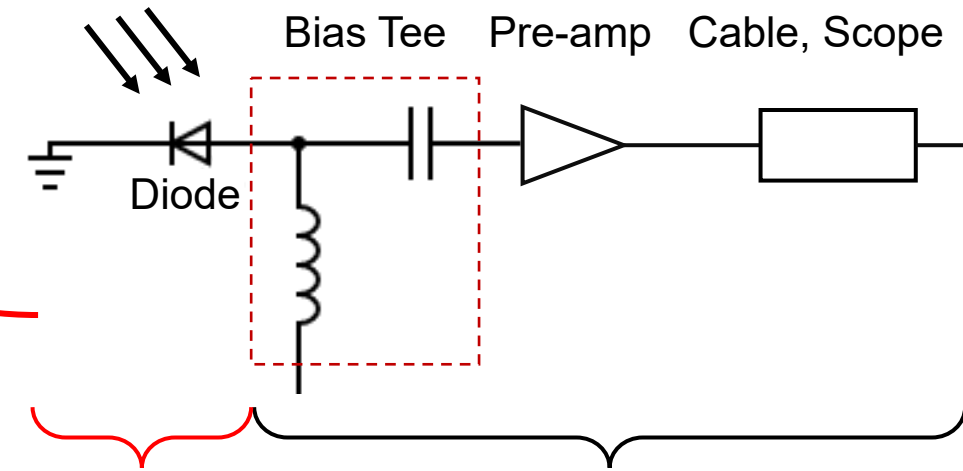
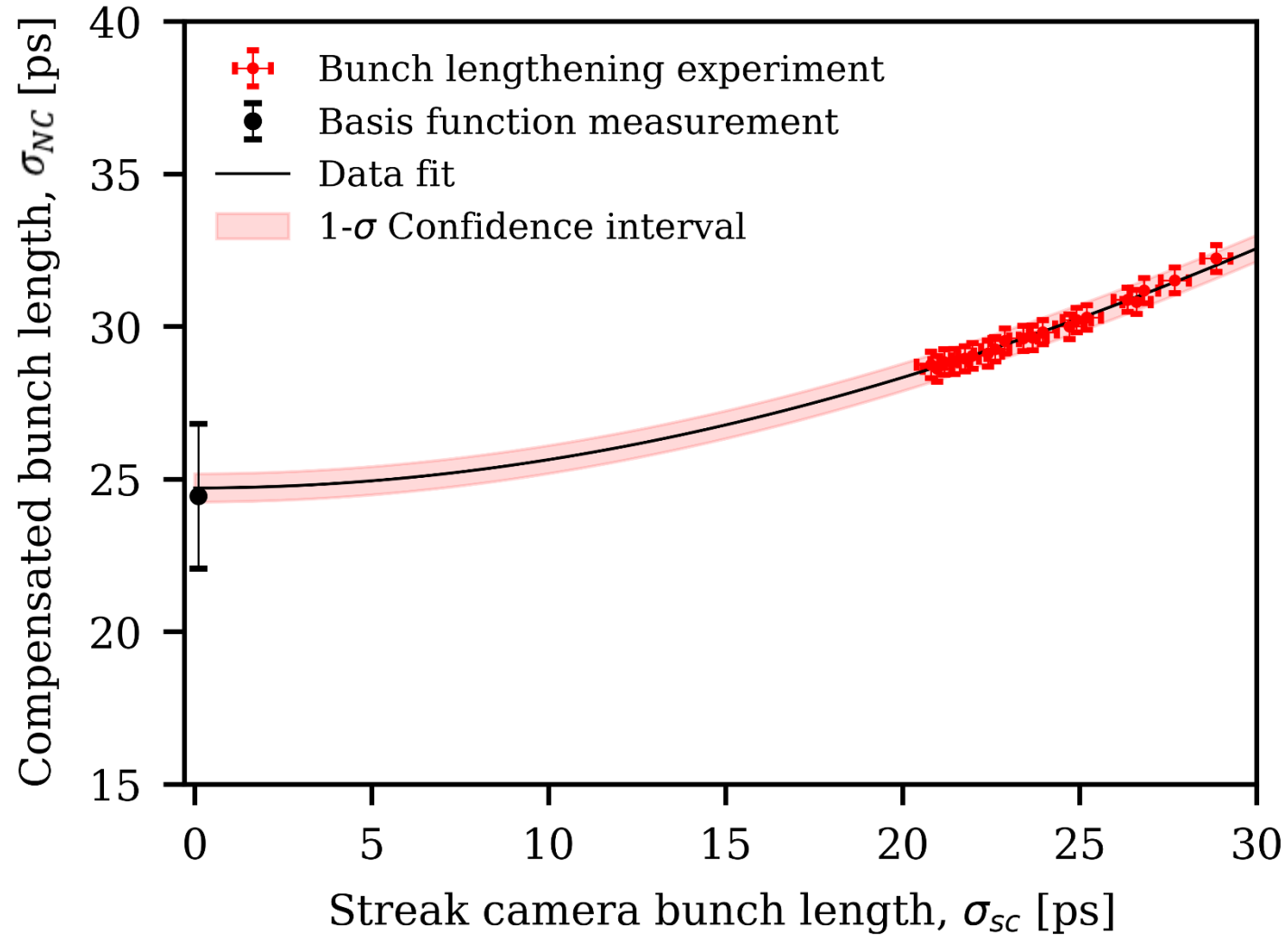
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- 2.5 Partitioning data-points into every RF bucket and converting time to phase

3. To find the bunch length, perform Gaussian fit

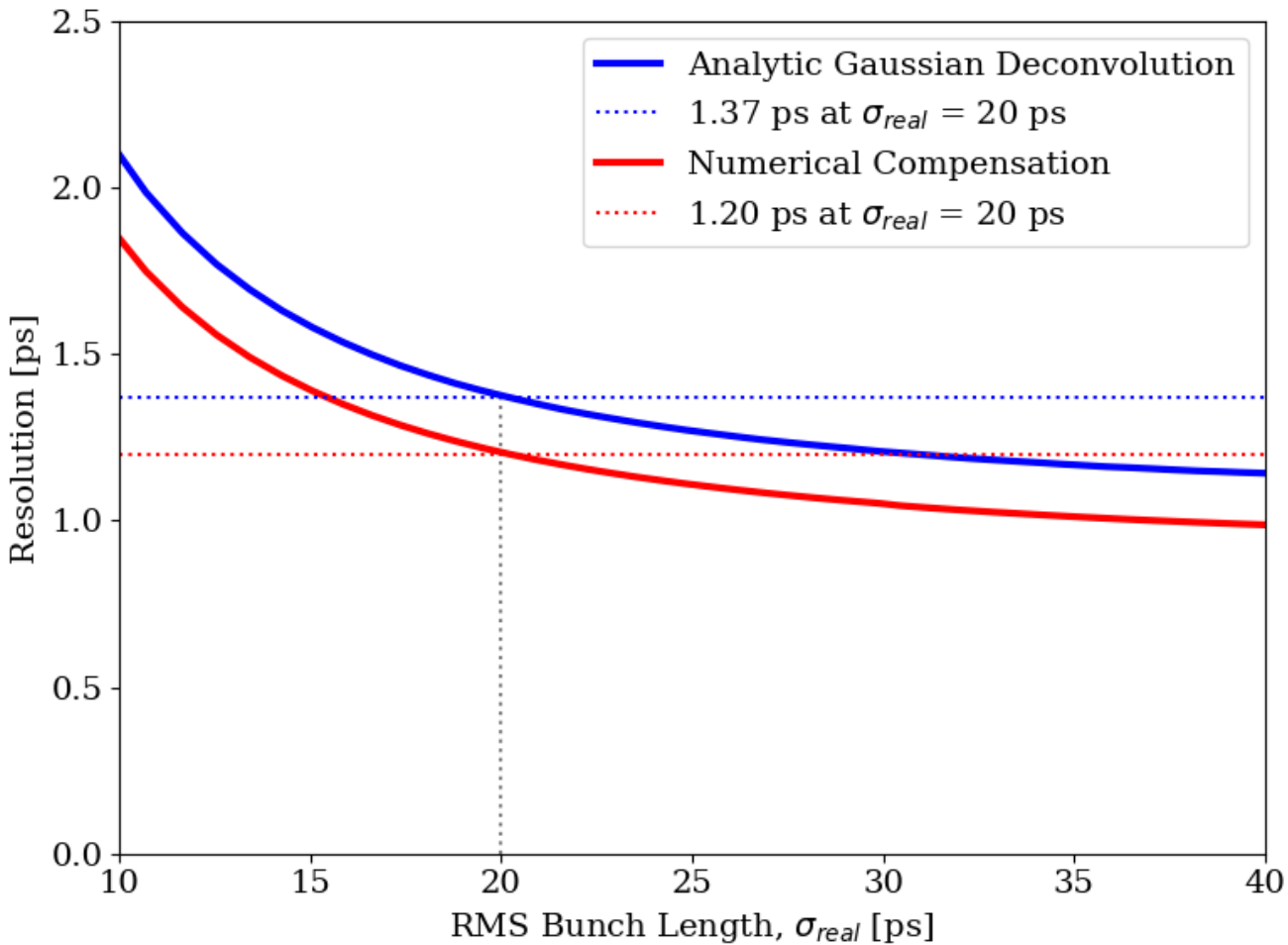
$$\sigma_{NC} = \sqrt{\sigma_{SC}^2 + A^2 + B}$$



What we don't know

Freq. Response Map

- The numerical compensation method lacks completeness since we don't know a Freq. response of the photodiode.
- However, in contrast to AGD, slope of quadratic curve was well matched.
- The extrapolated quadratic curve (Y interception point) is consistent with the laser experiment.
- Not perfect, but it is still a good method to provide longitudinal information in the operation range.



1. Artificially generate time domain signals $h_{MC}(t, \sigma_0)$

$$h_{MC}(t, \sigma_0) = h_{PSF,PD}(t)_{\sigma_0=0} * h_{IGB}(t, \sigma_0) * h_{BW}(t) + h_{MC\ NOISE}(t, \sigma_0)$$

- $h_{PSF,PD}|_{\sigma=0}(t)$: Point spread function (Gaussian profile $\sigma = 25.68$ ps)
- $h_{IGB}(t, \sigma_0)$: Ideal bunch-train profile
- $h_{BW}(t)$: Overall frequency response (PD, Amp, cable & digitizer)
- $h_{MC\ NOISE}(t, \sigma_0)$: Digitizer noise (random error based on technical note)

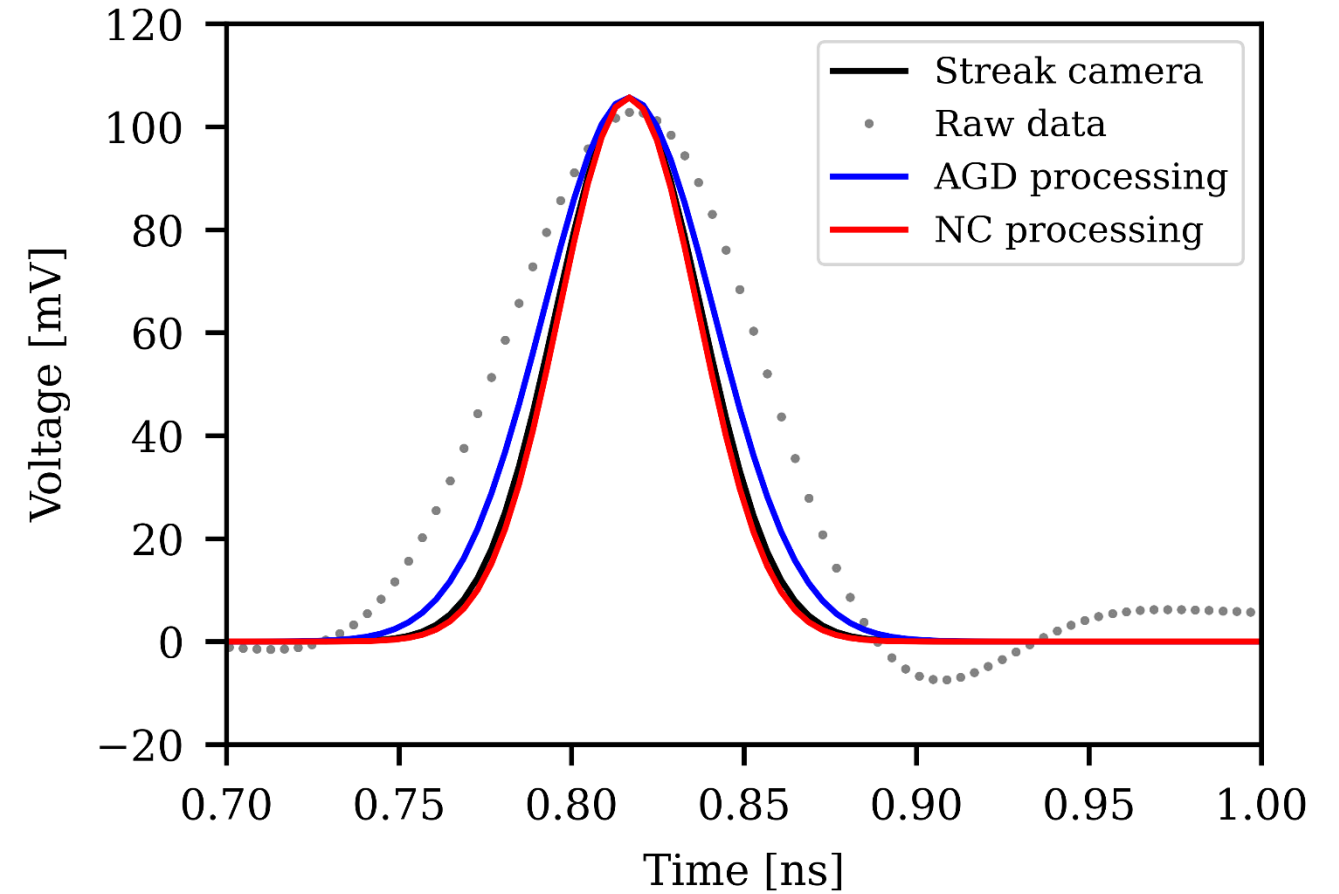
2. Calculate bunch length using both methods

$$\sigma_{AGD} \pm \sigma_{AGD\ fit\ error} \quad \sigma_{NC} \pm \sigma_{NC\ fit\ error}$$

3. Definition of systematic error

$$\sigma_{sys\ err} = \sqrt{\left(\frac{\sigma_{trigger\ jitter}}{N_{\#\ of\ meas}}\right)^2 + \sigma_{fit\ error}^2}$$

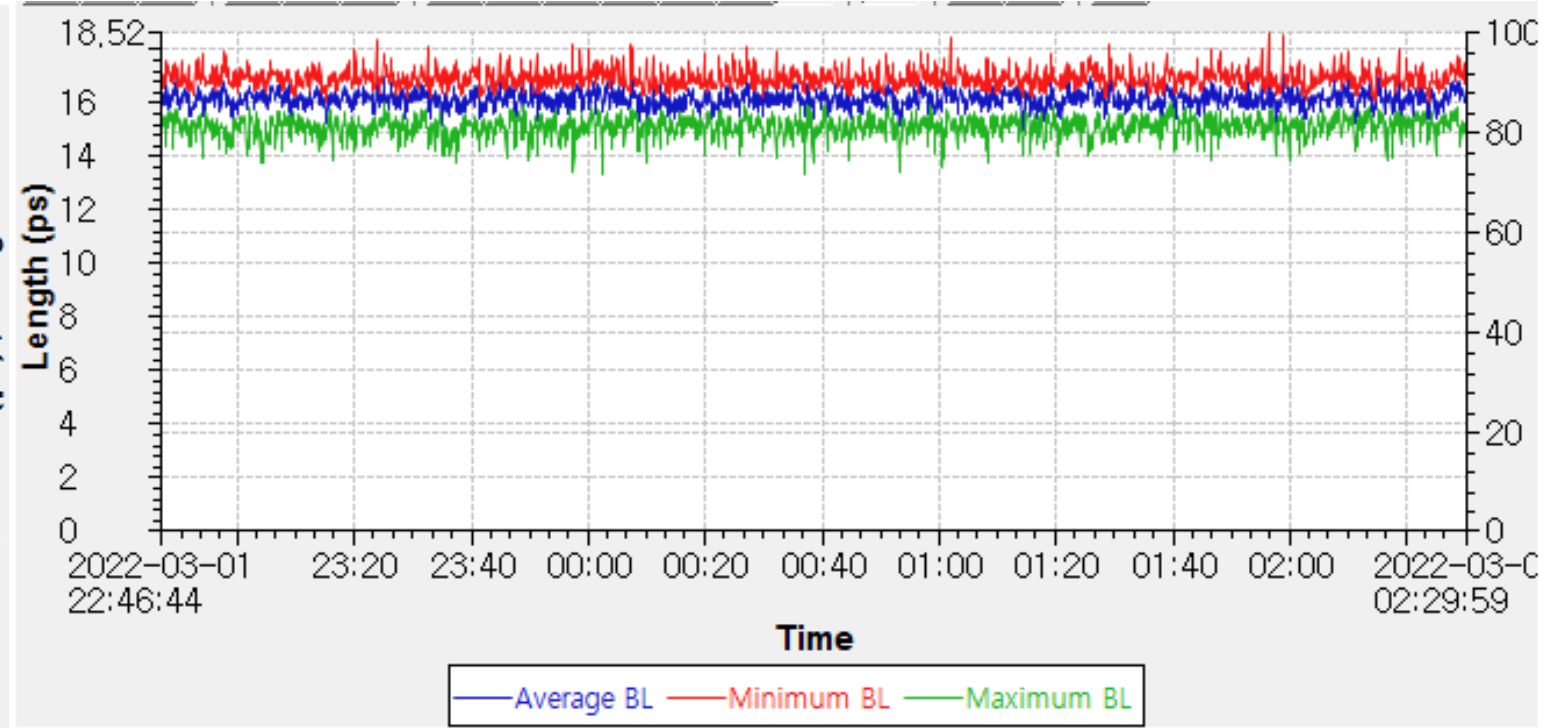
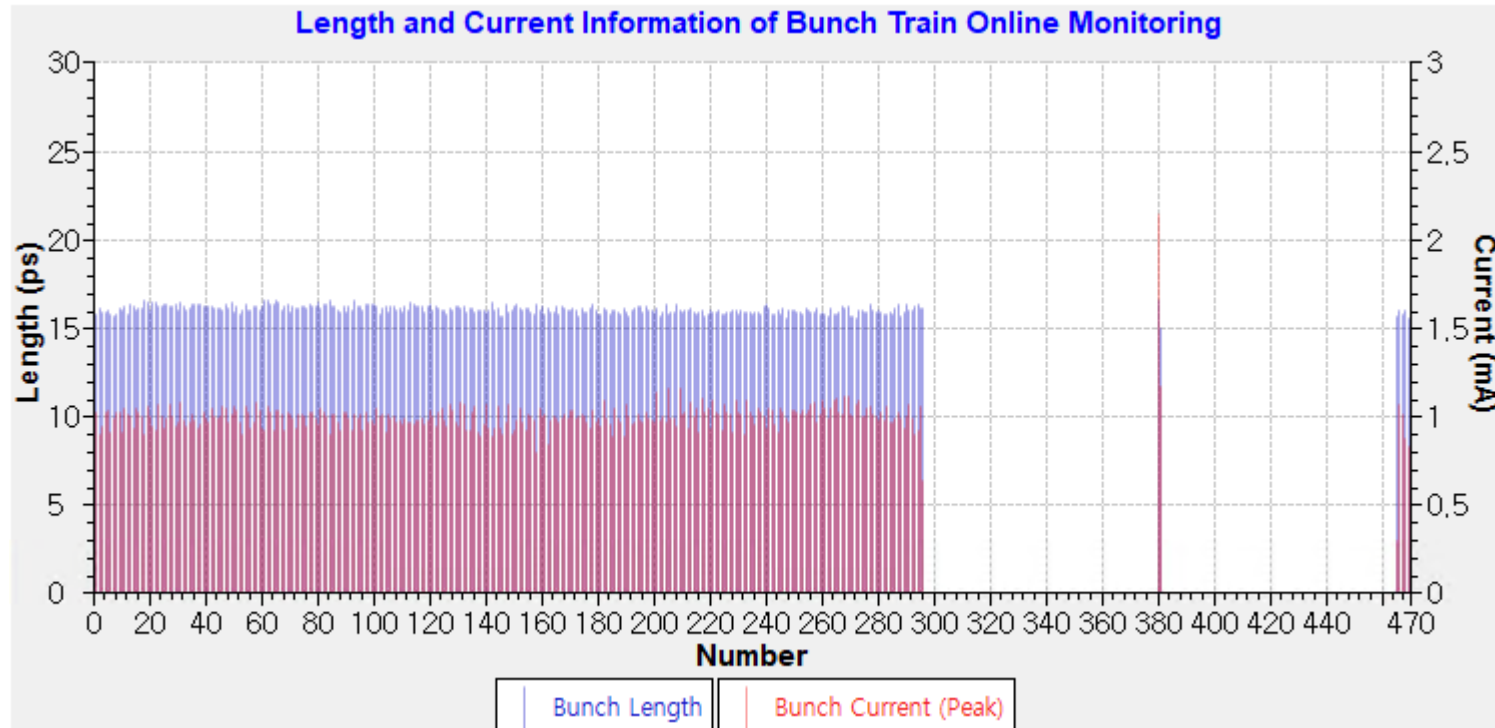
$$\sigma_{trigger\ jitter} = 30\ ps, \quad N_{\#\ of\ meas} = 500, \quad \sigma_{fit\ error} = \sigma_{AGD\ fit\ error} \ || \ \sigma_{NC\ fit\ error}$$



- The NC results are closest to the ideal curve, despite the absence of the photo-diode's frequency response
- BUT still we could not understand why the fit form looks like below

$$\sigma_{NC} = \sqrt{\sigma_{SC}^2 + A^2 + B}$$

We are monitoring bunch length online

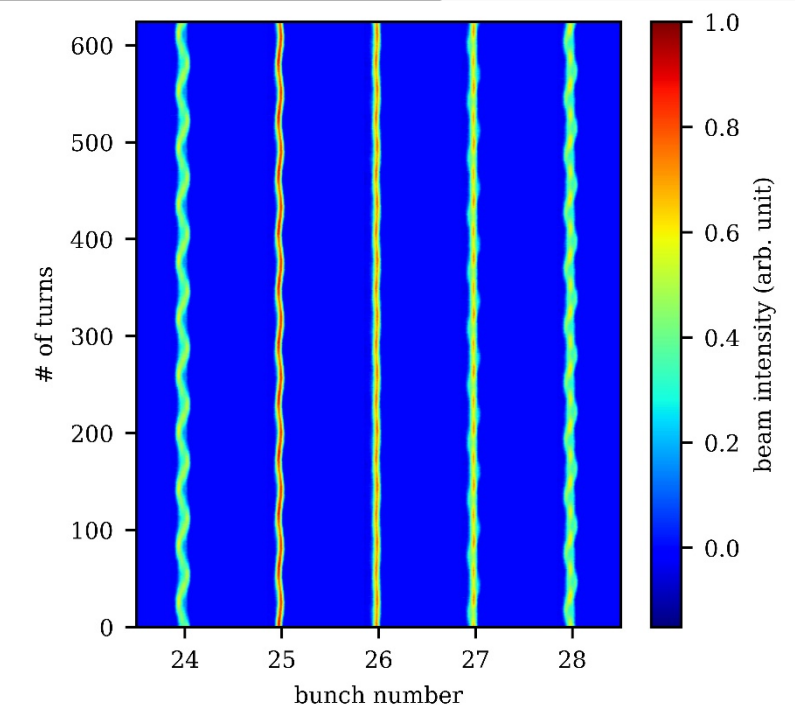


Old system (with Picoscope-9404-16, Pico Technology):

- Data acquisition time : 30 ~ 120 seconds for statistically mitigating the error mainly due to the revolution trigger jitter of 30 ps and vertical noise of the scope.

New system (with DPO71304SX, Tektronix):

- Real time data acquisition : PV updating rate is about 0.1 ~ 1.0 Hz (mostly data transferring time)
- Trigger jitter free (non-averaged)



- We have experimentally demonstrated a compact monitor that enables filling pattern ($\sim 3 \mu\text{A}$ resolution) and bunch length ($\sim 1 \text{ ps}$ resolution) monitoring with visible light at the PLS-II storage ring
- Both analytical Gaussian deconvolution and numerical compensation methods were investigated to improve measurement accuracy
 - We achieved better resolution with numerical compensation method
- Recently we installed a new digitizer for online Turn-by-turn and Bunch-by-bunch measurements are under contemplation as a future upgrade project.

Thank you for your attention



IBIC2023